

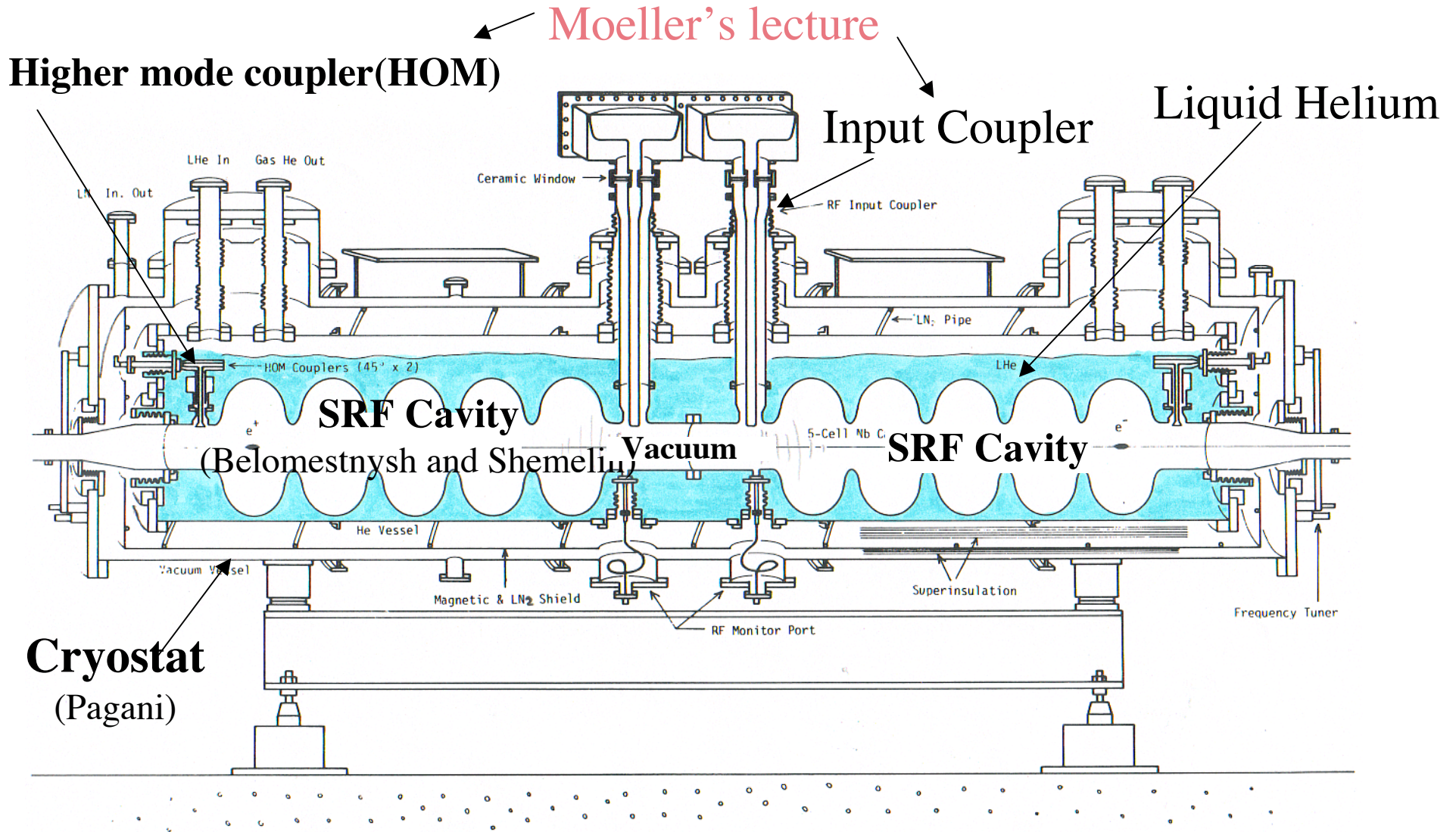
Basic Principles of SRF

**High Energy Accelerator Research Organization
KEK, Accelerator Lab**

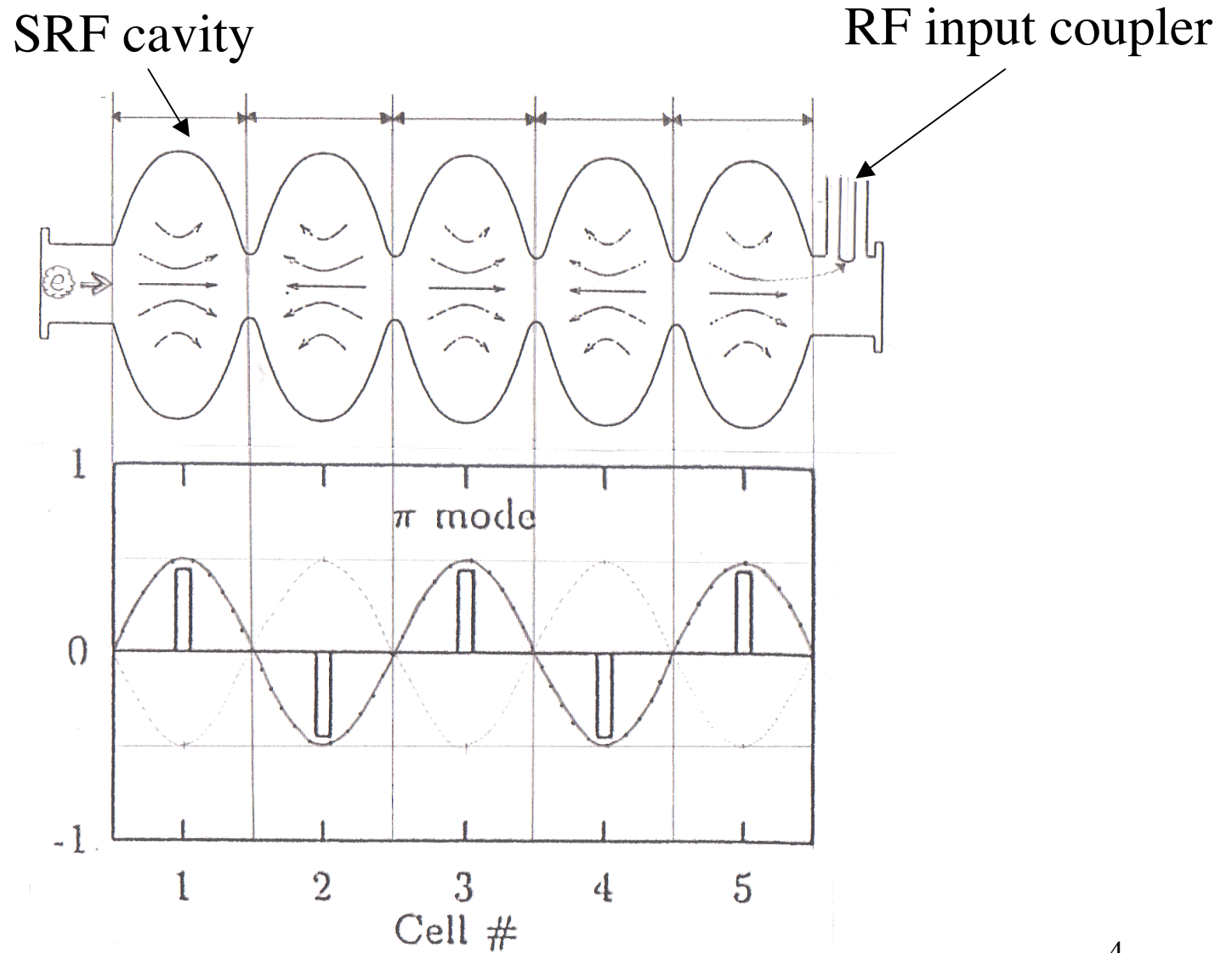
Kenji Saito

Introduction

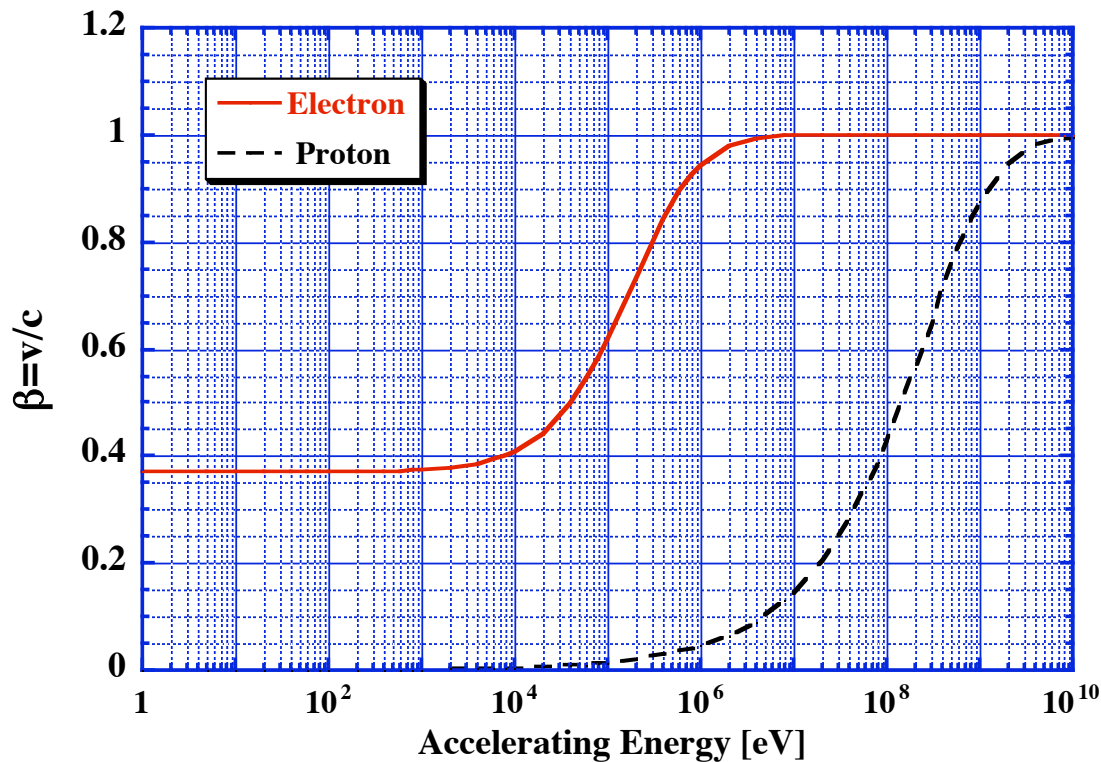
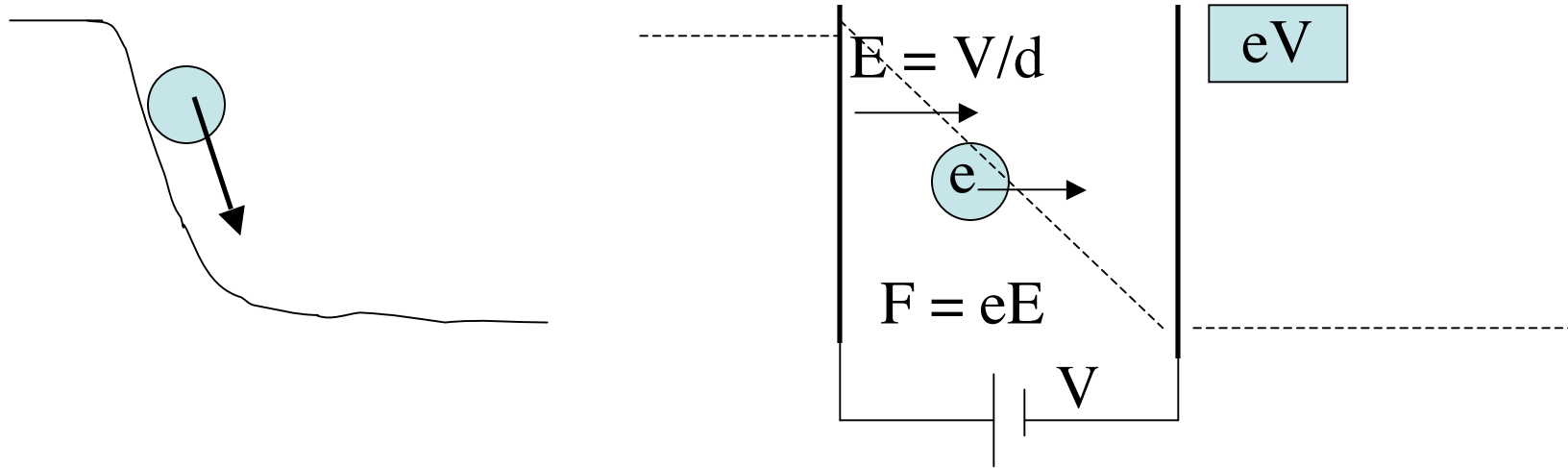
An example of real SRF Cryomodule (TRISTAN)



Principle of RF particle acceleration



Charged Particle Acceleration

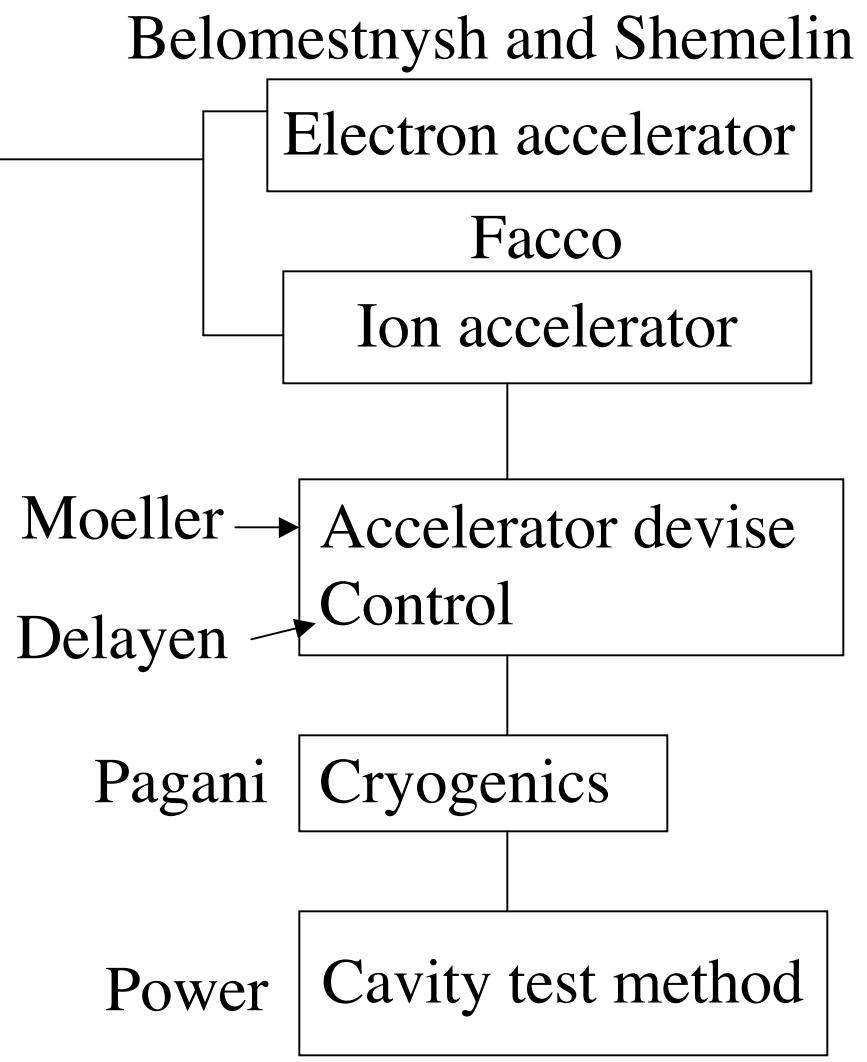
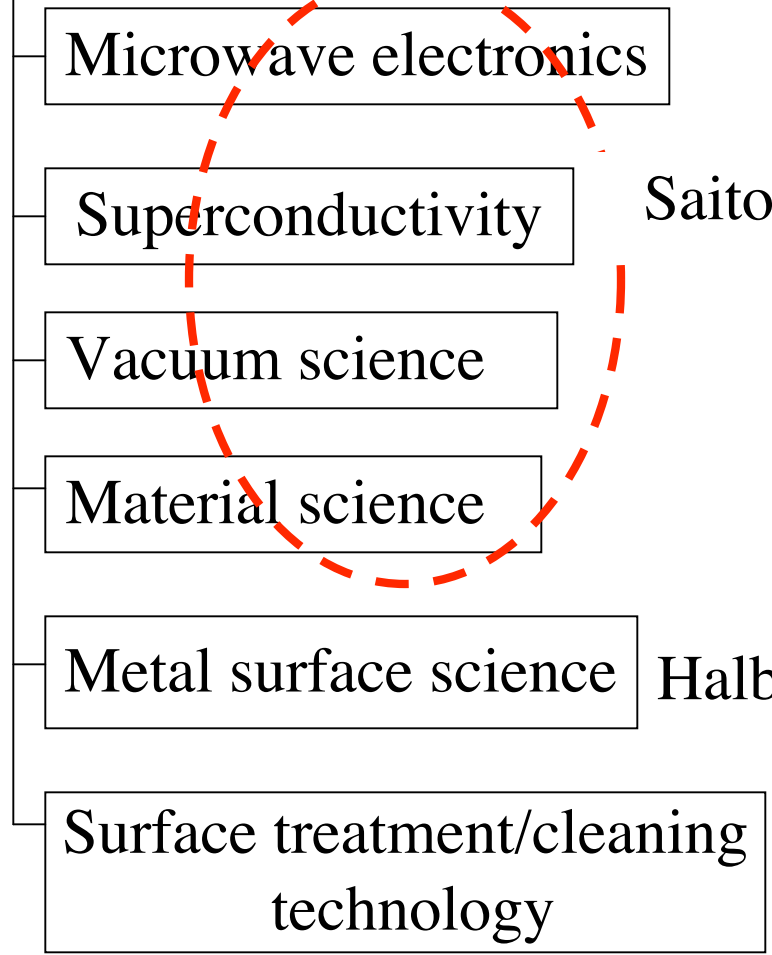


$$mc^2 = \frac{m_0 c^2}{\sqrt{1 - \left(\frac{v}{c}\right)^2}} = \frac{m_0 c^2}{\sqrt{1 - \beta^2}} = m_0 c^2 + W,$$

$$\beta = \sqrt{1 - \left(\frac{m_0 c^2}{m_0 c^2 + W}\right)^2}, \quad m_e c^2 = 0.511 \text{ MeV},$$

$$m_p c^2 = 938.256 \text{ MeV}$$

SRF technology for particle accelerators



Q1: Why RF loss in SRF Cavities

Q2: What is the theoretical SRF field limitation

Q3: What kind of SC material is best for SRF application

**Q4: Thermal Conductivity in Superconducting State and
Residual Resistance Ratio (RRR)**

**Q5: Real SRF field limitation and
Technologies to push gradient**

Surface Impedance

For plane wave: $\vec{E}_t = E_0 \exp(i\vec{k} \cdot \vec{x} - i\omega t)$, $\vec{H}_t = \frac{1}{\mu\omega} \vec{k} \times \vec{E}_t$
here, \vec{k} is orthogonal to \vec{E}_t .

$$\text{Surface impedance : } Z \equiv R_s + iX_s \equiv \frac{E_t}{H_t} = \frac{\mu\omega}{k}$$

$$\text{For good conductor } \sigma \gg 1, \quad k = (1+i) \sqrt{\frac{\mu\sigma\omega}{2}}$$

$$Z = \mu\omega \sqrt{\frac{2}{\mu\sigma\omega}} \cdot \frac{1}{1+i} = \mu\omega \sqrt{\frac{2}{\mu\sigma\omega}} \cdot \frac{1-i}{2} = (1-i) \sqrt{\frac{\mu\omega}{2\sigma}}$$

$$R_s = \sqrt{\frac{\mu\omega}{2\sigma}} = \frac{1}{\sigma} \sqrt{\frac{\mu\sigma\omega}{2}} = \frac{1}{\sigma\delta}$$

σ : electric conductivity
 δ : skin depth

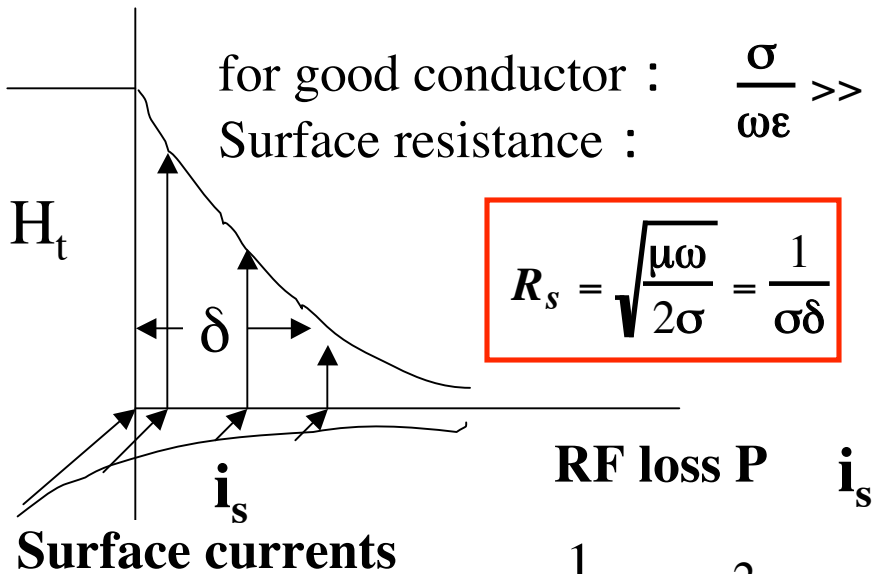
Why RF loss in SRF cavities

Normal conducting

δ : skin depth of microwave

for good conductor : $\frac{\sigma}{\omega\epsilon} \gg 1$
 Surface resistance :

$$R_s = \sqrt{\frac{\mu\omega}{2\sigma}} = \frac{1}{\sigma\delta}$$



Surface currents

Metal

RF loss P

$$P = \frac{1}{2} R_s \int i_s^2 ds$$

$$= \frac{1}{2} R_s \int H_s^2 ds$$

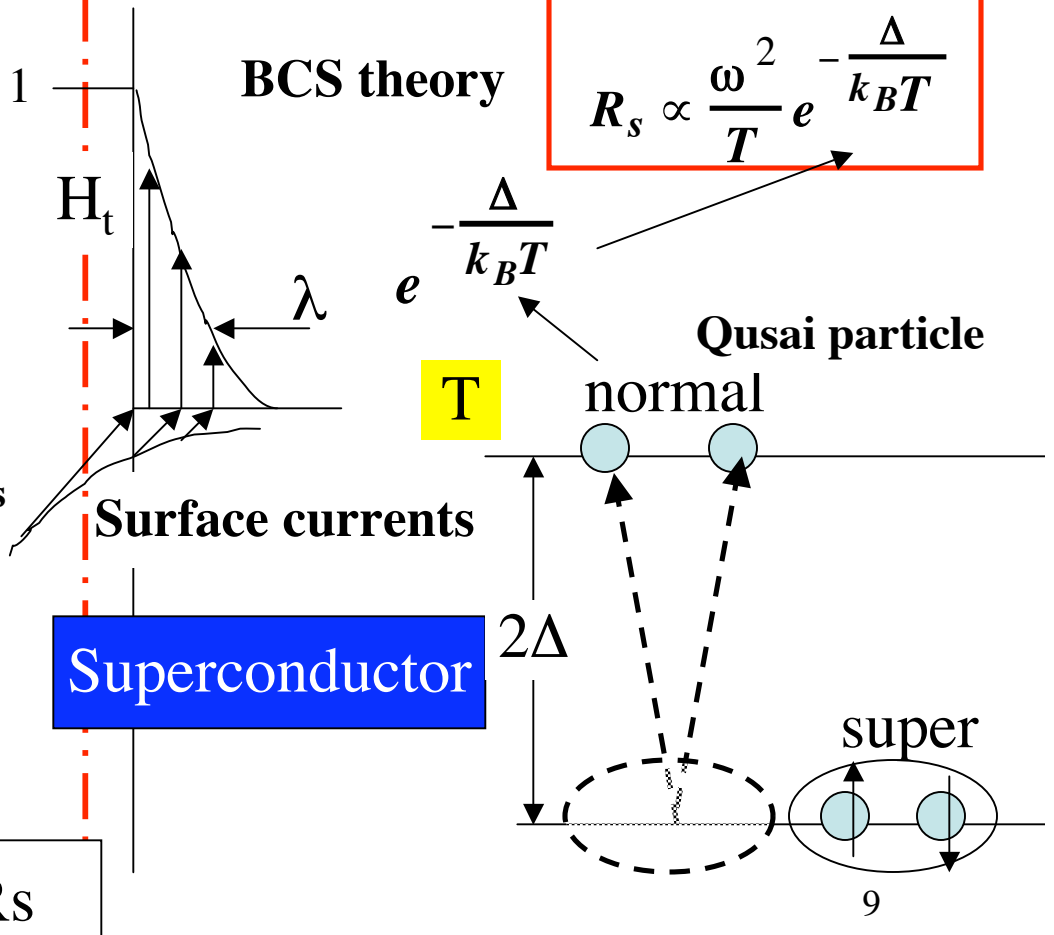
$$Q_0 = \omega U / P_{loss} = G / R_s$$

Superconducting

λ : London penetration depth

BCS theory

$$R_s \propto \frac{\omega^2}{T} e^{-\frac{\Delta}{k_B T}}$$



Surface currents

Superconductor

T

normal

Quasi particle

2Δ

super

RF surface resistance in superconductor-Two Fluid model-

General equation: $m \frac{\partial \vec{v}}{\partial t} = q(\vec{E} + \vec{v} \times \vec{B}) - m \vec{v} \nabla$

Two-fluid model

$$\vec{J} = \vec{J}_s + \vec{J}_n, \quad \vec{J}_s = n_s q_s \vec{v}_s, \quad \vec{J}_n = n_n q_n \vec{v}_n$$

Maxwell equation: neglecting the Lorentz term, $\vec{v} \times \vec{B} \ll 1$

$$m_s \frac{\partial \vec{v}_s}{\partial t} = q_s \vec{E}, \quad m_s = 2m_e, \quad q_s = 2 \cdot (-e)$$

$$m_e \frac{\partial \vec{v}_n}{\partial t} = q_n \vec{E} - m_e \nabla \cdot \vec{v}_n, \quad q_n = -e$$

$$\vec{E} = \vec{E}_0 e^{i\omega t} \Rightarrow \vec{J}_s = \frac{n_s q_s^2}{i\omega m_s} \vec{E}, \quad \vec{J}_n = \frac{n_n e^2}{i(\omega - i\nu)} \vec{E}$$

$$\vec{J} = \left(\frac{n_s q_s^2}{i\omega m_s} + \frac{n_n e^2}{i(\omega - i\nu) m_e} \right) \vec{E}$$

$$\nu > \omega \Rightarrow \vec{J} = \left(\frac{n_n e^2}{\nu m_e} - i \frac{n_s q_s^2}{\omega m_s} \right) \vec{E} = (\sigma_n - i\sigma_s) \vec{E} = \sigma \vec{E}$$

$$\sigma = \sigma_n - i\sigma_s$$

$$\begin{aligned}
Z &= (1-i)\sqrt{\frac{\mu\omega}{2\sigma}} = (1-i)\sqrt{\frac{\mu\omega}{2(\sigma_n - i\sigma_s)}} \\
&= (1-i)\sqrt{\frac{\mu\omega}{2}} \cdot \frac{1}{\sqrt{-i\sigma_s(1 - \sigma_n / i\sigma_s)}} \\
&\approx (1-i)\sqrt{\frac{\mu\omega}{2}} \cdot \frac{(1 + \frac{\sigma_n}{i2\sigma_s})}{\sqrt{-i\sigma_s}} \\
&= \sqrt{\mu\omega} \left(\frac{\sigma_n}{2\sigma_s^{3/2}} + i \frac{1}{\sigma_s^{1/2}} \right) \quad Q \sqrt{-i} = \sqrt{e^{-\frac{\pi}{2}}} = \frac{(1-i)}{\sqrt{2}}
\end{aligned}$$

$$Z = \frac{\mu\omega\lambda^3}{\delta^2} + i\mu\omega\lambda = \frac{\mu^2\omega^2\lambda^3\sigma_n}{2} + i\omega\mu\lambda$$

Here, $\lambda = \sqrt{\frac{m_s}{n_s q_s^2 \mu}} = c \sqrt{\frac{2m}{4n_s \mu e^2}} = c \sqrt{\frac{m}{2n_s \mu e^2}}$ London penetration depth

Surface resistance in superconductor

$$\sigma_n = \frac{n_n \cdot e^2 \cdot l}{m \cdot v_F} = \frac{e^2 \cdot l}{m \cdot v_F} \cdot n_s(T=0) \cdot e^{-\frac{\Delta}{k_B T}}$$

$$R_S = \frac{1}{2} \cdot (2\pi)^2 \cdot \mu^2 \cdot f^2 \cdot \lambda_L^3 \cdot l \cdot \frac{n_s(0)}{m v_F} \cdot e^{-\frac{\Delta}{k_B T}}$$

$$= A \cdot f^2 \cdot e^{-\frac{\Delta}{k_B T}}$$

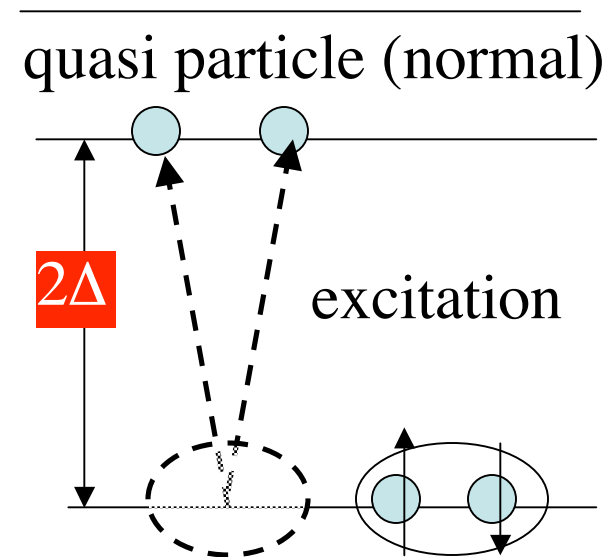
BCS theory

$$R_{BCS}(T, f) = A(\lambda, \xi, l, T_c) \cdot \frac{f^2}{T} \cdot e^{-\frac{\Delta}{k_B T}}$$

$\Delta/k_B = 1.76T_c$ by BCS theory

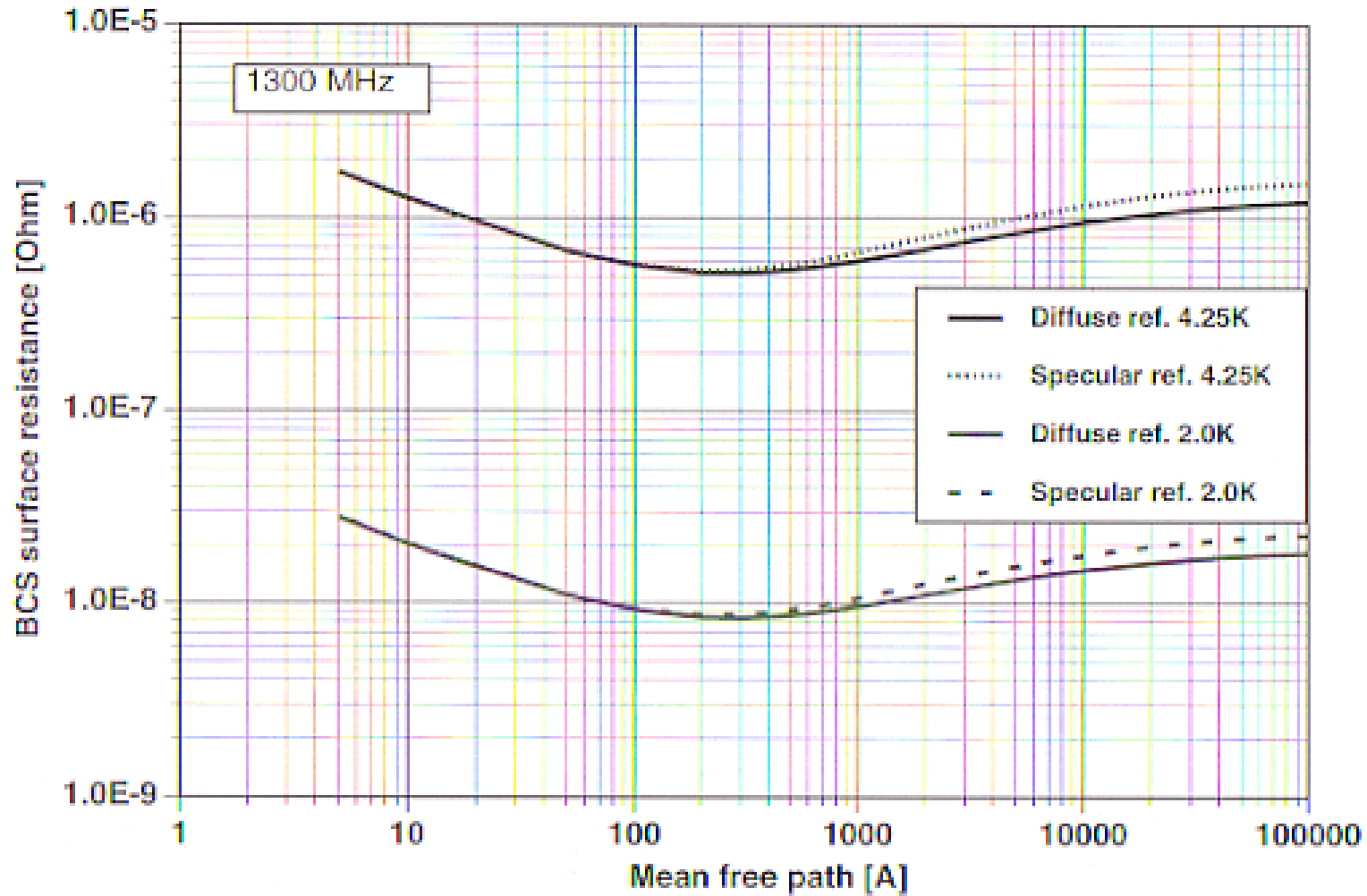
Higher T_c material produces lower R_{BCS}

At a finite temperature T



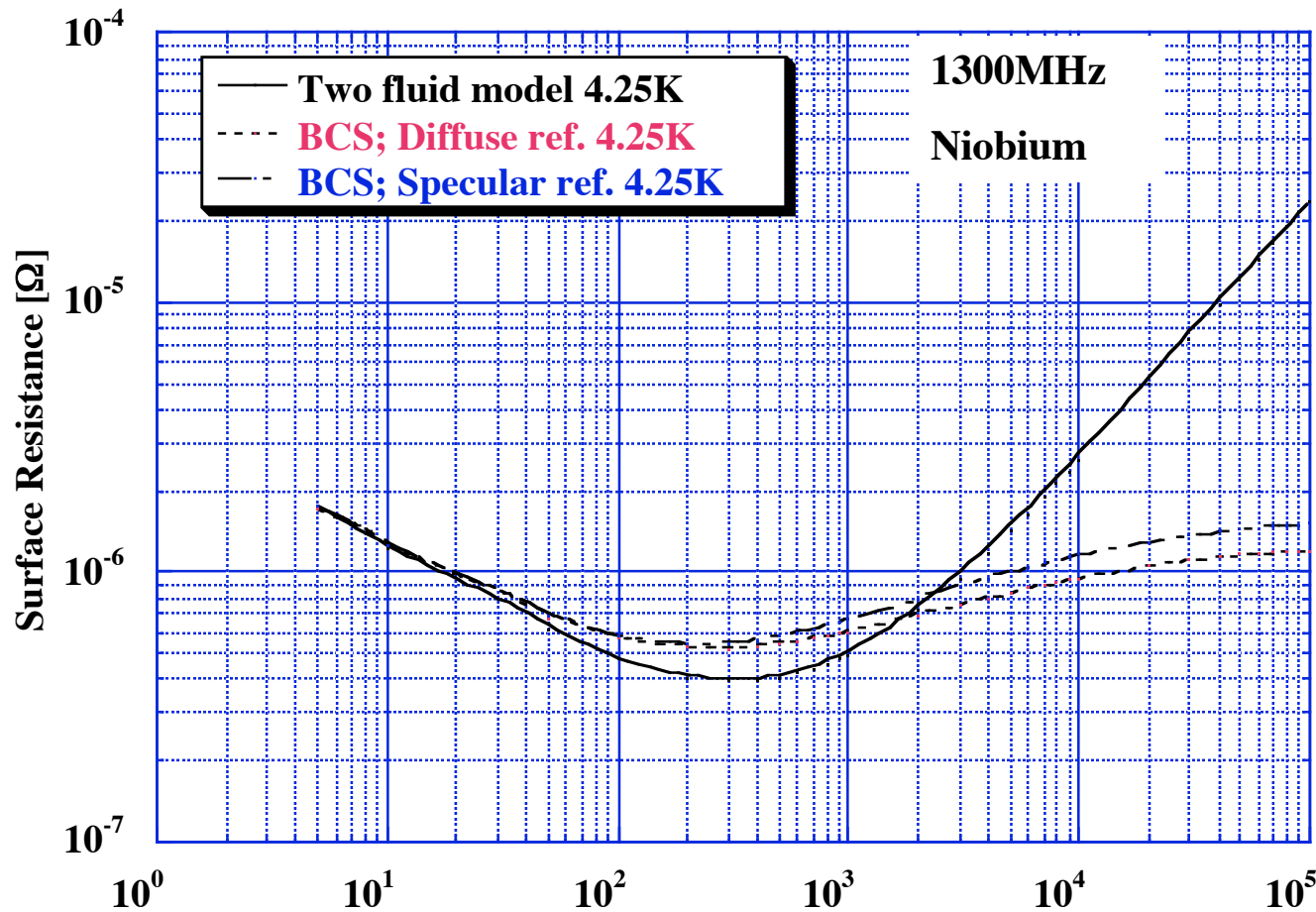
R_{BCS} at 2 and 4.25K

Used Harbriter's code



$R_{BCS} \sim 8n\Omega @ 2K, 1300MHz$

Minimum of R_{BCS}



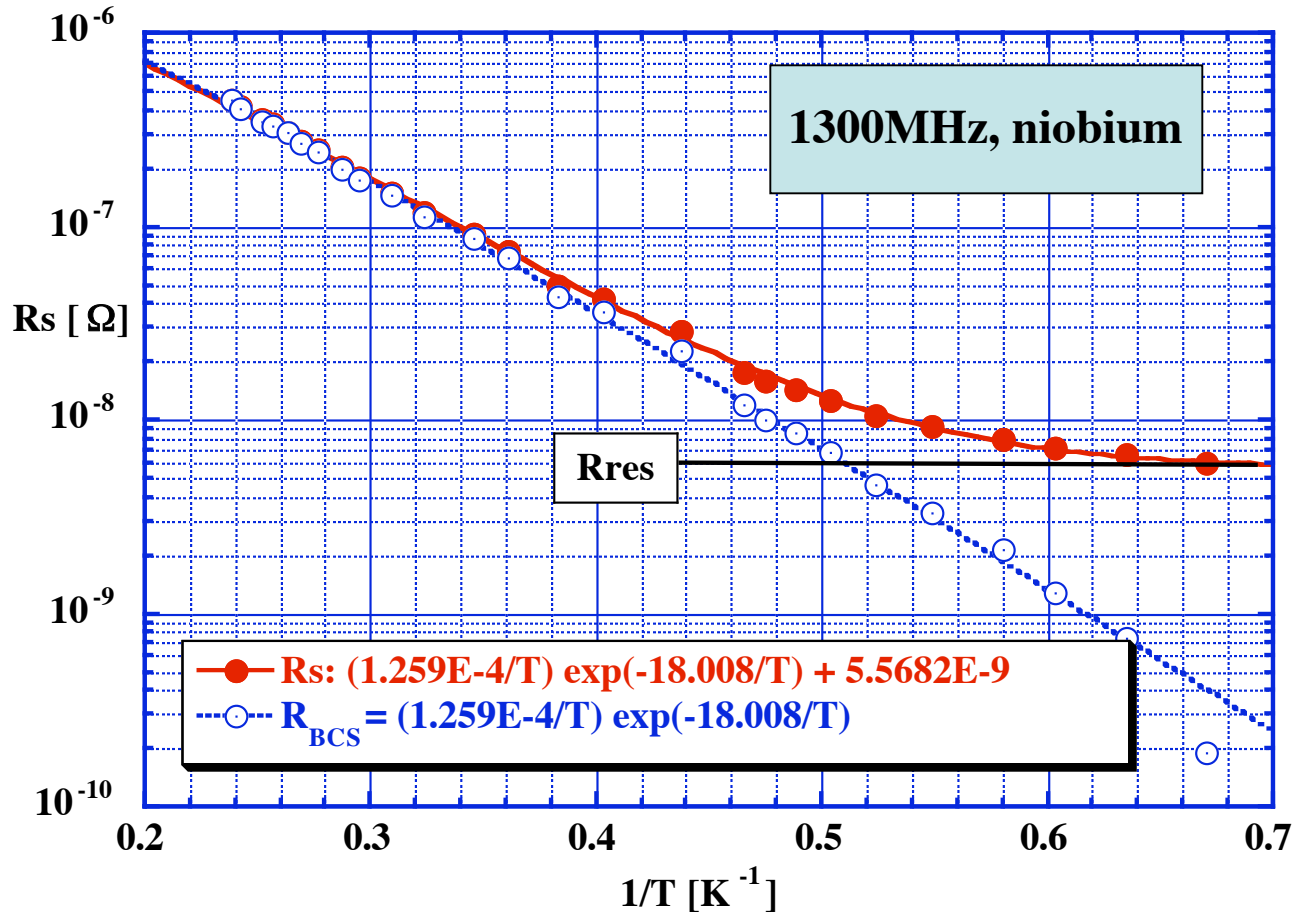
Strange behavior of R_{BCS} for mean free pass l

R_{BCS} minimum at
 $l \approx 200 \sim 300$

$$l [A] = 20 \cdot RRR$$

$$\lambda_L(l) = \lambda_L(l = \infty) \cdot \sqrt{1 + \frac{\xi_o}{l}}, \quad R_S (TF \text{ model}) \propto (1 + \frac{\xi_o}{l})^{\frac{3}{2}} \cdot l, \quad l \ll 1, R_S \rightarrow \frac{\xi_o^{\frac{3}{2}}}{\sqrt{l}}, \quad l \gg 1, R_S \rightarrow l$$

Measurement of the Surface resistance



$$\frac{\Delta}{k_B} = 18.008 \Rightarrow \frac{2\Delta}{k_B T_c} = \frac{2 \cdot 18.008}{9.25} = 3.89$$

$$\frac{2\Delta}{k_B T_c} = 3.52 \text{ (BCS theory)}$$

Due to surface contamination, residual magnetic field in the cryostat.

$R_{BCS} \sim 8n\Omega$,
Quit fit to BCS theory.

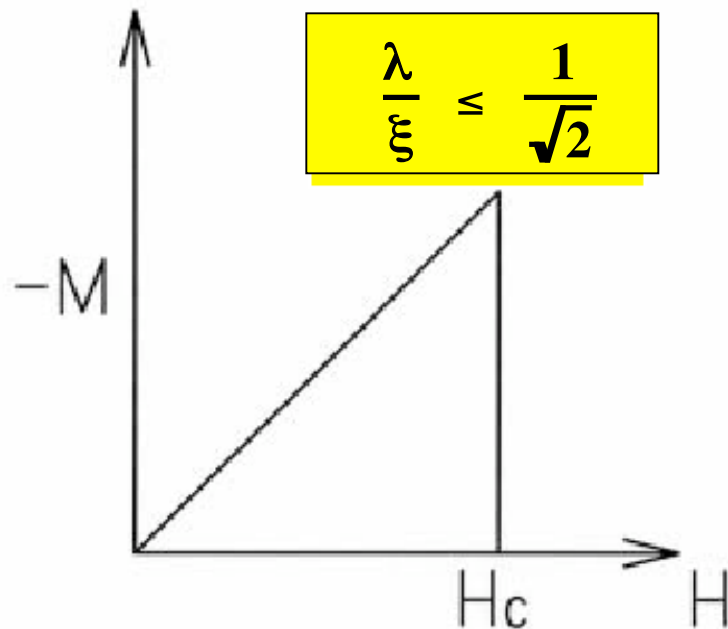
Real surface resistance : $R_s = R_{BCS}(T) + R_{res}$

Q2: Theoretical SRF field limitation

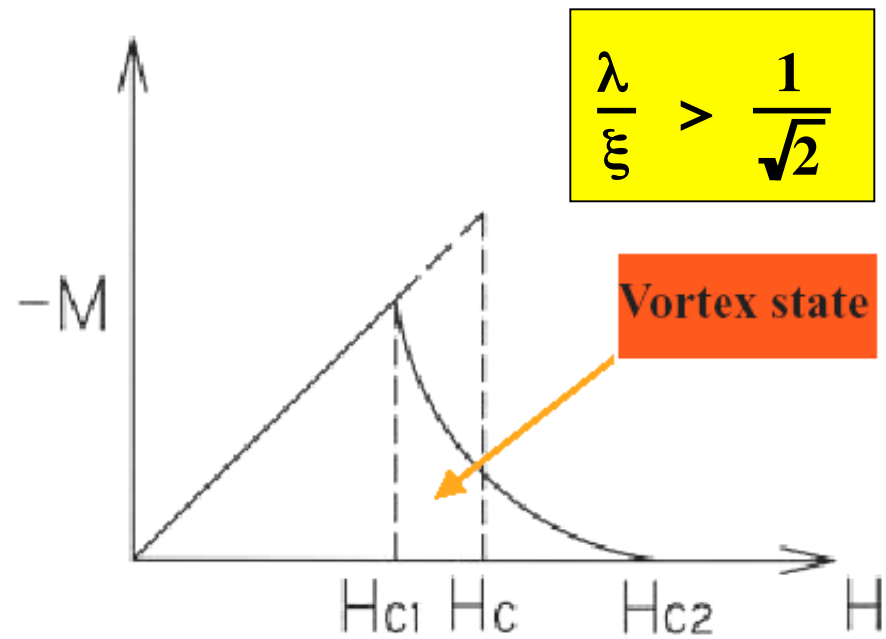
Q3: What kind of SC material is best for SRF application ?

Two types of superconductor

Type-I

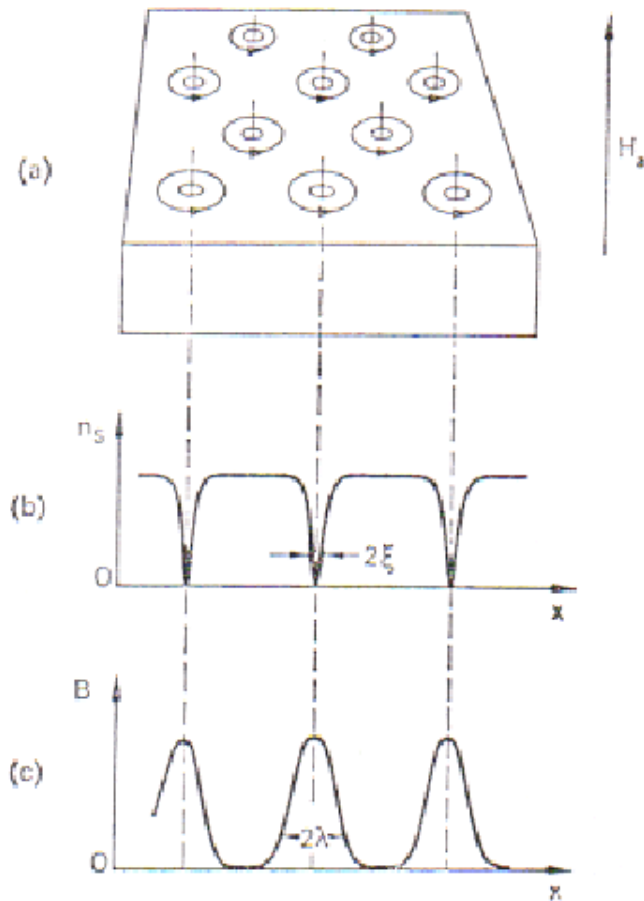


Type-II



$\frac{\lambda}{\lambda_L} \equiv \kappa$: Ginzburg - Landau Parameter

Vortex state



Vortex state

ξ : Coherence length
size of Cooper pair

λ_L : London penetration depth

Depth of penetration of the magnetic field

Observed vortex

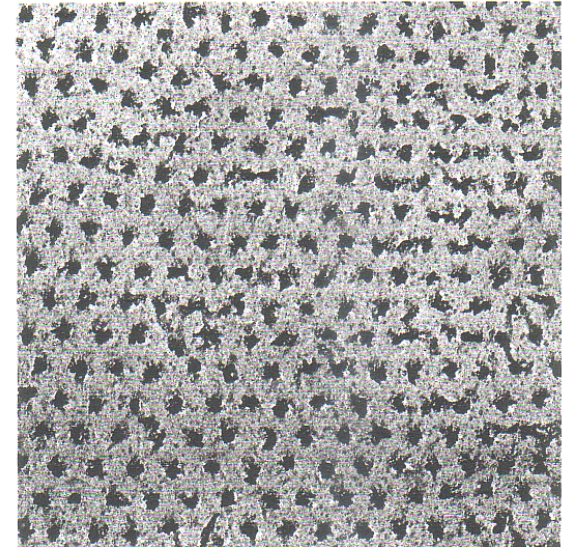
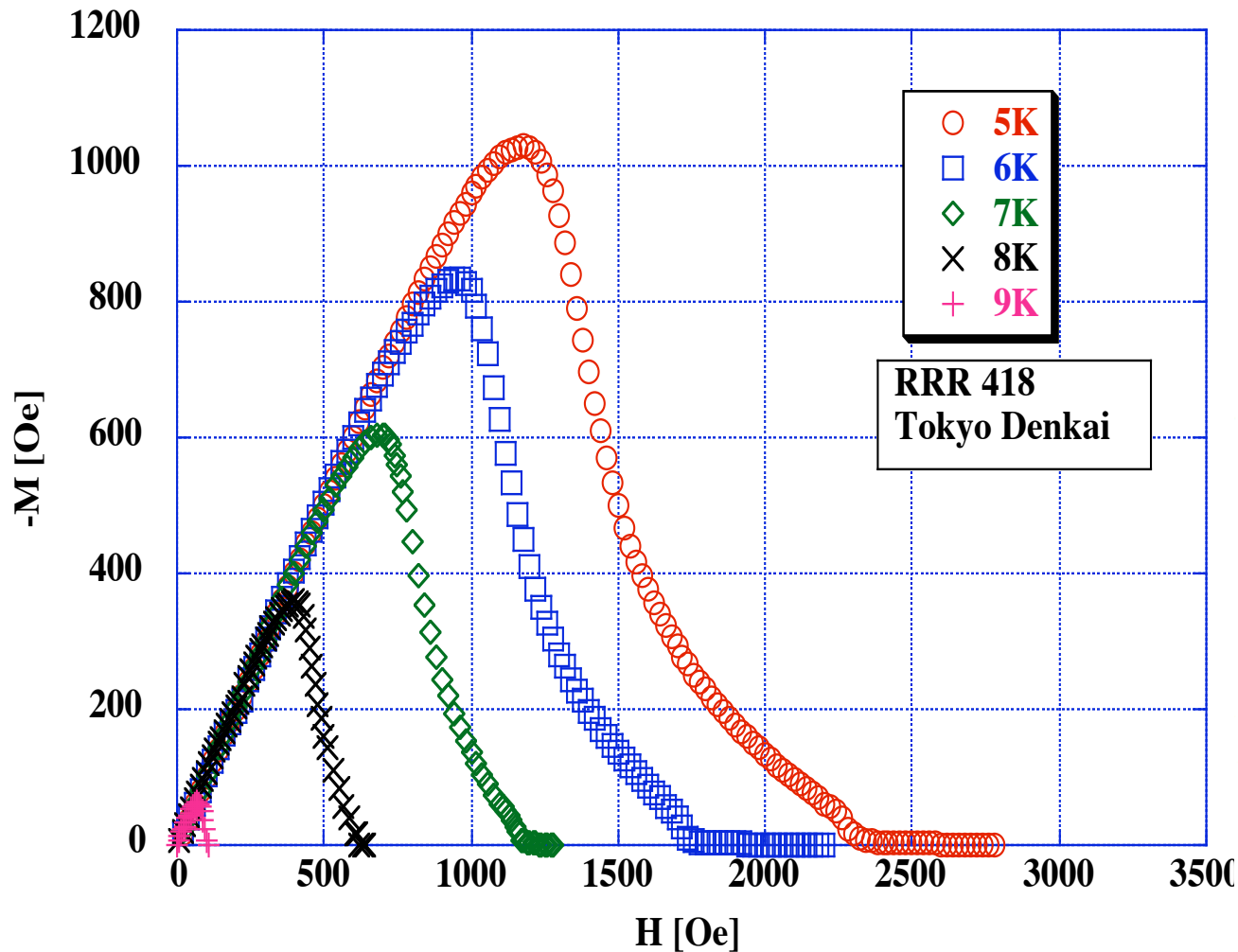


Figure 19 Triangular lattice of fluxoids through top surface of a superconducting cylinder. The points of exit of the flux lines are decorated with fine ferromagnetic particles. The electron microscope image is at a magnification of 8300, by U. Essmann and H. Trüble.

Hc measurement

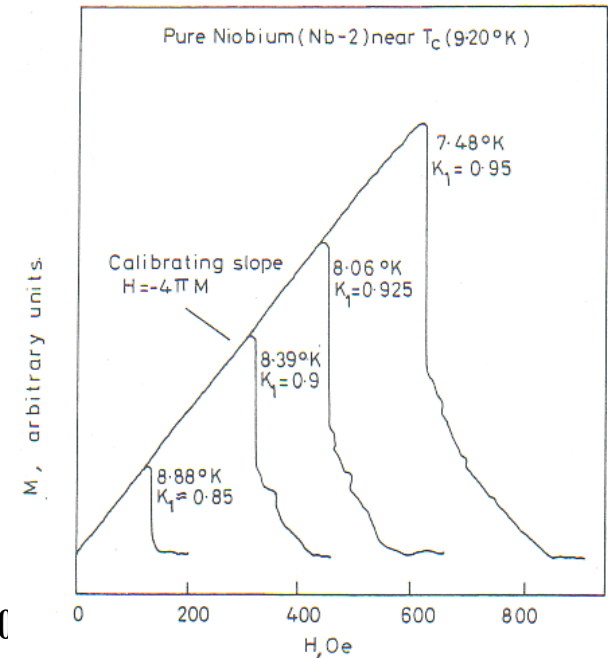
Industrial material

Industrial Nb material is how different
With magnetic property from lab material.



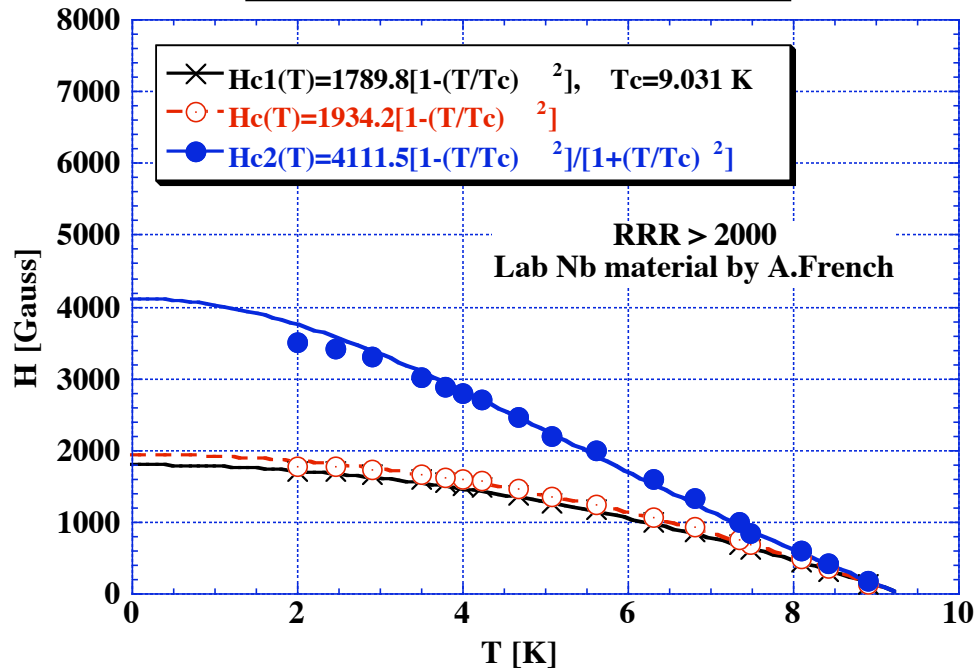
$$F_n - F_s = -\int_0^H c^2 M dH = \frac{1}{2} \mu H_c^2$$

Lab material RRR~2000

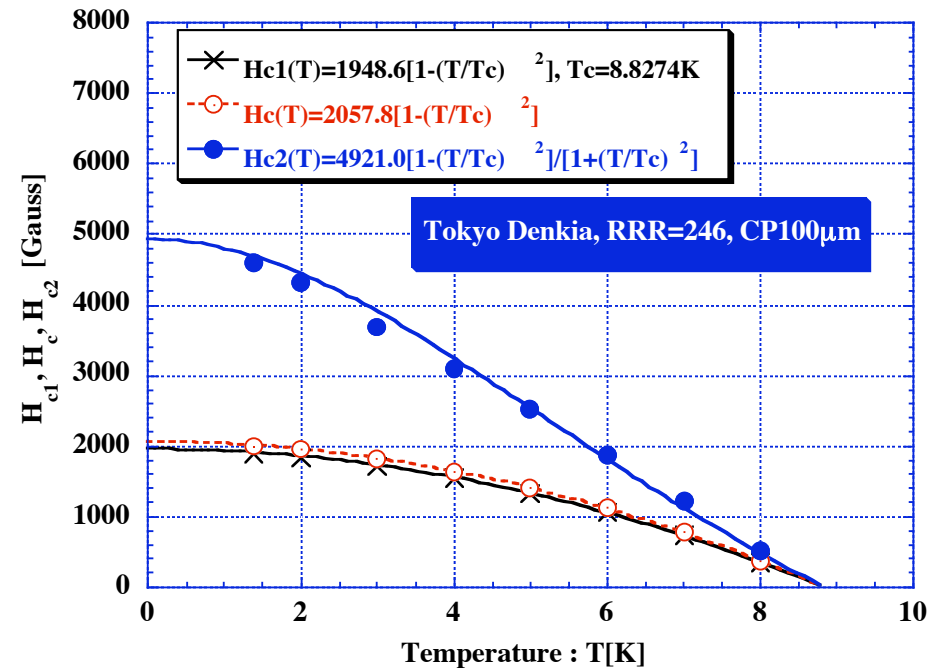


Measurement results with H_{c1} , H_c , H_{c2}

Lab Nb material



Industrial produced Nb material



$$H_c(T) = H_c(0) \cdot \left[1 - \left(\frac{T}{T_c} \right)^2 \right], \quad F_n - F_s = -\int_0^{H_{c2}} M dH = \frac{1}{2} \mu H_c^2$$

$$H_{c2}(T) = H_{c2}(0) \cdot \frac{[1 - (T/T_c)^2]}{[1 + (T/T_c)^2]}$$

Later you will derive this from
Abrikosov theory.

Abrikosov Theory: Theory for Type-II SC

$$H_c = \frac{\kappa}{\lambda^2} \frac{hc}{\sqrt{2e}^*} = \frac{\kappa}{\lambda^2} \frac{(hc/2e)}{2\pi\sqrt{2}} = \frac{\phi_0}{2\pi\sqrt{2}\lambda\xi}$$

$$H_{c2} = \sqrt{2} \frac{\lambda}{\xi} \frac{\phi_0}{2\pi\sqrt{2}\lambda\xi} = \frac{\phi_0}{2\pi\xi^2}$$

$$H_{c1} = \frac{\phi_0}{4\pi\lambda^2} \ln\left(\frac{\lambda}{\xi} + 0.08\right)$$

$$\begin{aligned}\phi_0 &= hc/2e = 2.0678 \times 10^{-7} \text{ Gauss} \cdot \text{cm}^2 \\ &= 2.0678 \times 10^{-15} \text{ T} \cdot \text{m}^2\end{aligned}$$

T-dependence of λ , ξ , κ

Abrikosov theory

$$\xi = \sqrt{\frac{\phi_0}{2\pi \cdot H_{c2}}} , \quad \lambda = \sqrt{\frac{\phi_0 \cdot H_{c2}}{4\pi \cdot H_c^2}}$$

From both theory and experiment $\lambda(T), H_c(T)$ are:

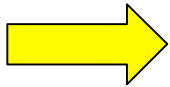
$$\lambda(T) = \frac{\lambda(0)}{\sqrt{1 - \left(\frac{T}{T_c}\right)^4}} , \quad H_c(T) = H_c(0) \cdot \left[1 - \left(\frac{T}{T_c}\right)^2\right]$$

$$H_{c2}(T) = \frac{4\pi\lambda(T)^2}{\phi_0} \cdot H_c(T)^2 = \frac{4\pi\lambda(0)^2 \cdot H_c(0)^2}{\phi_0} \cdot \frac{\left[1 - (T/T_c)^2\right]^2}{1 - (T/T_c)^4}$$

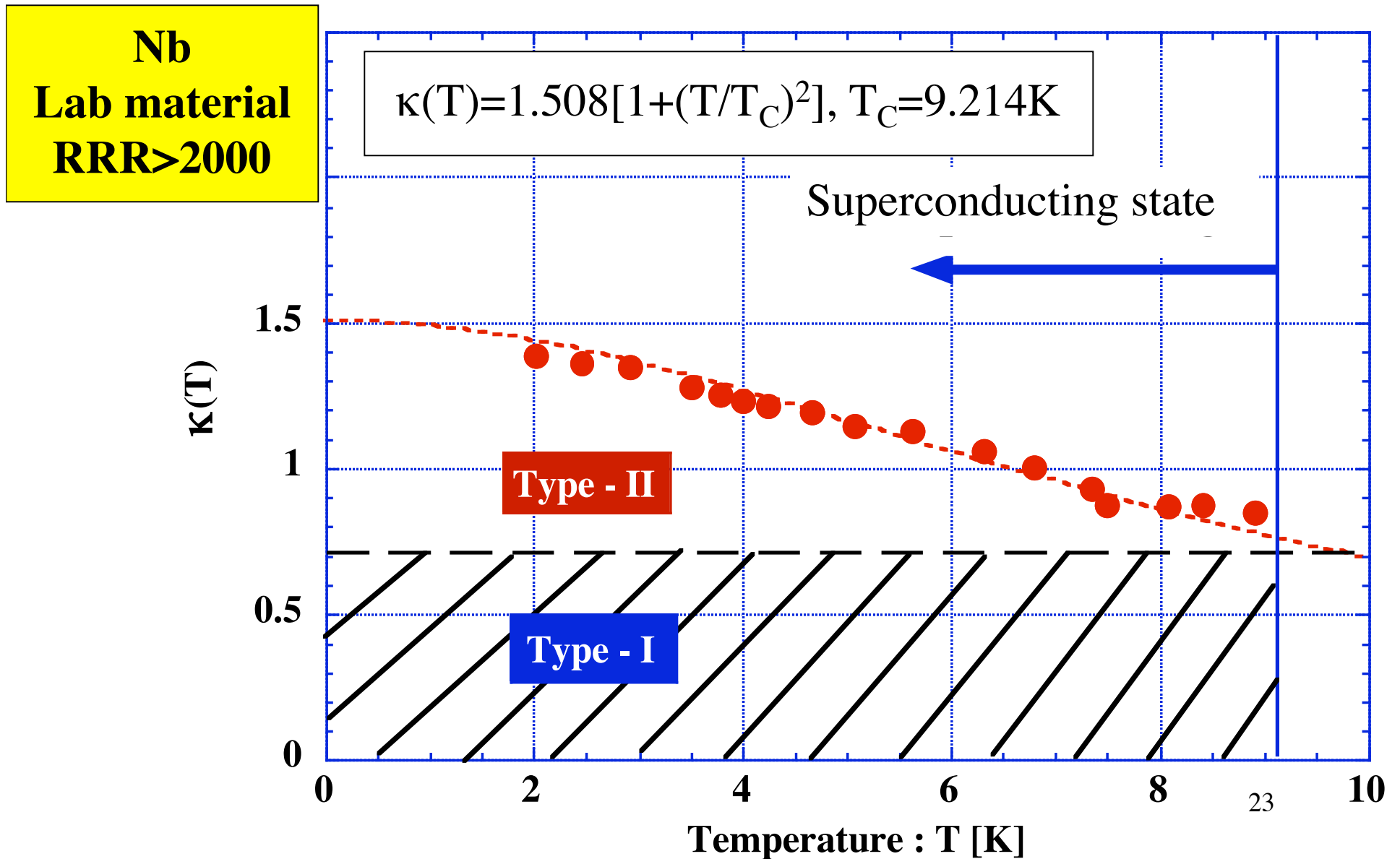
$$= H_{c2}(0) \cdot \frac{1 - (T/T_c)^2}{1 + (T/T_c)^2}$$

$$\xi(T) = \sqrt{\frac{\phi_0}{2\pi \cdot H_{c2}(0)}} \cdot \sqrt{\frac{1 + (T/T_c)^2}{1 - (T/T_c)^2}} = \xi(0) \cdot \sqrt{\frac{1 + (T/T_c)^2}{1 - (T/T_c)^2}}$$

$$\frac{\lambda(T)}{\xi(T)} \equiv \kappa(T) = \frac{1}{\sqrt{2}} \cdot \frac{H_{c2}(T)}{H_c(T)} = \frac{H_{c2}(0)}{\sqrt{2} \cdot H_c(0)} \cdot \frac{1}{1 + (T/T_c)^2} = \frac{\kappa(0)}{1 + (T/T_c)^2}$$



T-dependence of κ with Lab material



Critical field limitation in SRF application

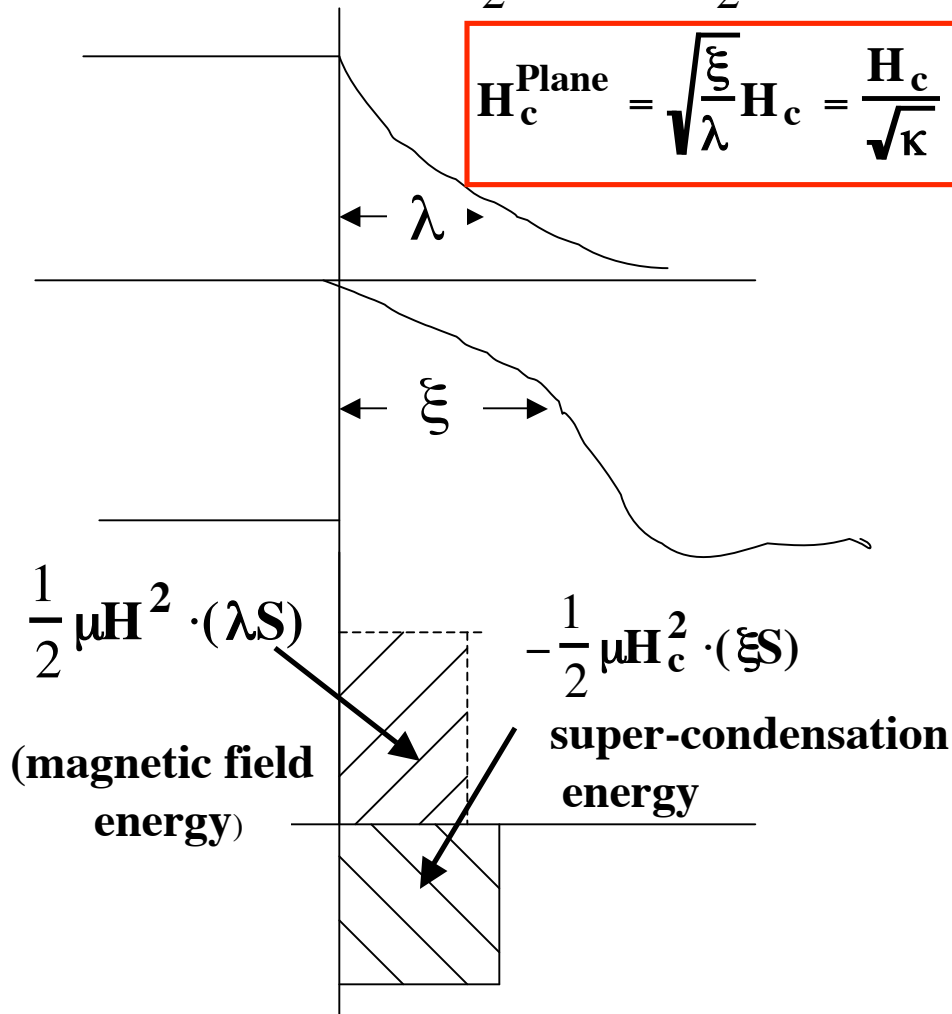
Vortex plane nucleation

Type-I

H:effective value

$$\frac{1}{2} \mu H^2 \cdot \lambda - \frac{1}{2} \mu H_c^2 \cdot \xi = 0$$

$$H_c^{\text{Plane}} = \sqrt{\frac{\xi}{\lambda}} H_c = \frac{H_c}{\sqrt{\kappa}}$$

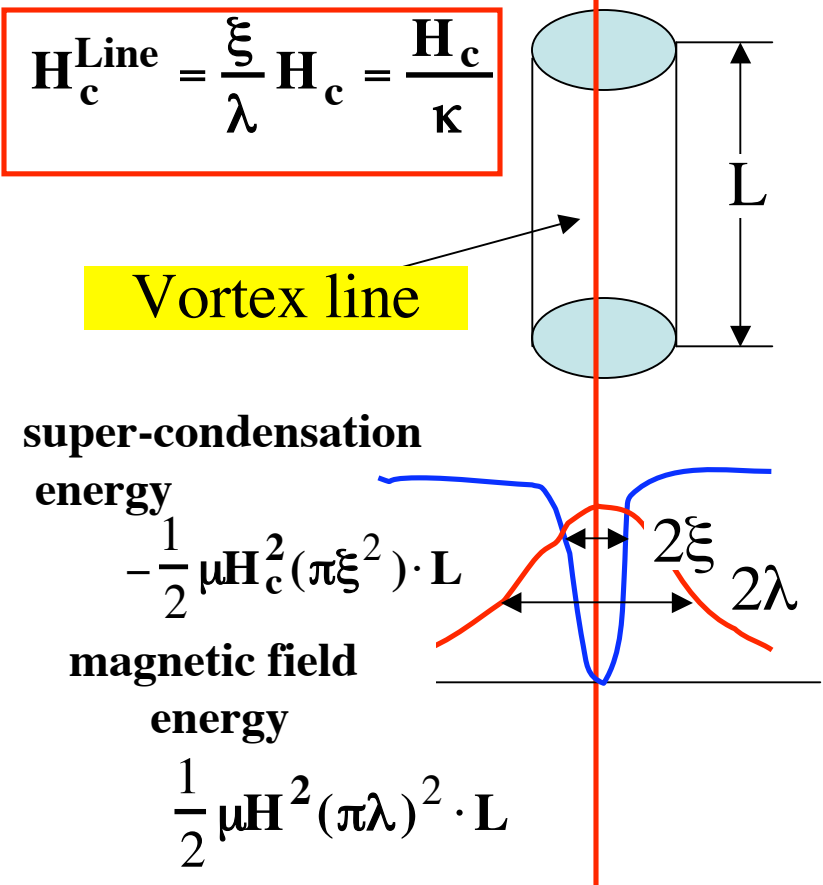


Vortex line nucleation

Type-II

$$\frac{1}{2} \mu H^2 \lambda^2 - \frac{1}{2} \mu H_c^2 \xi^2 = 0$$

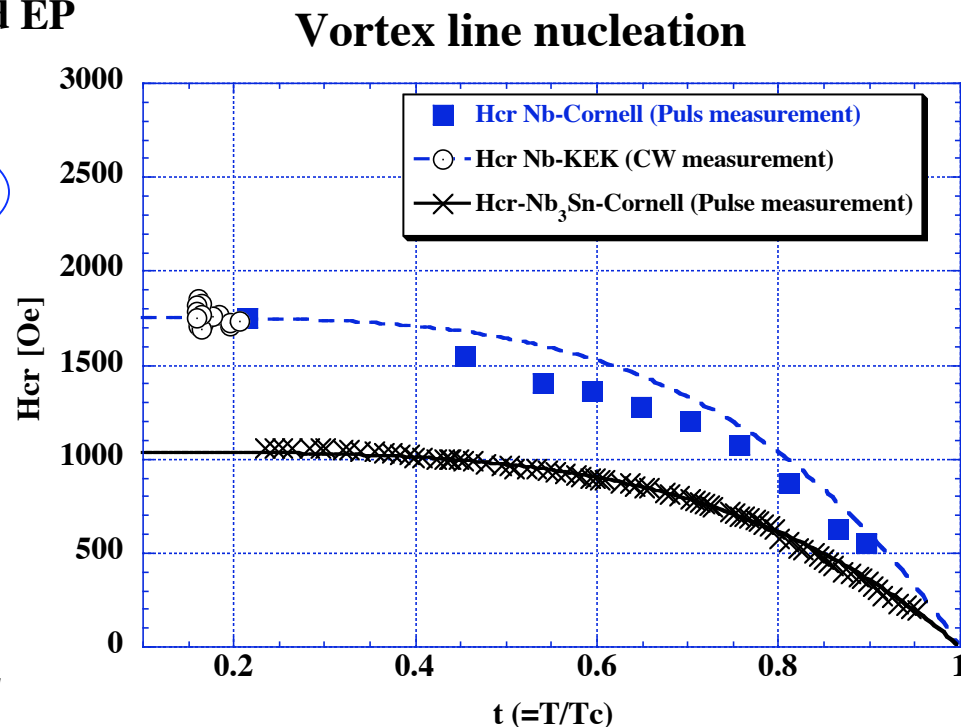
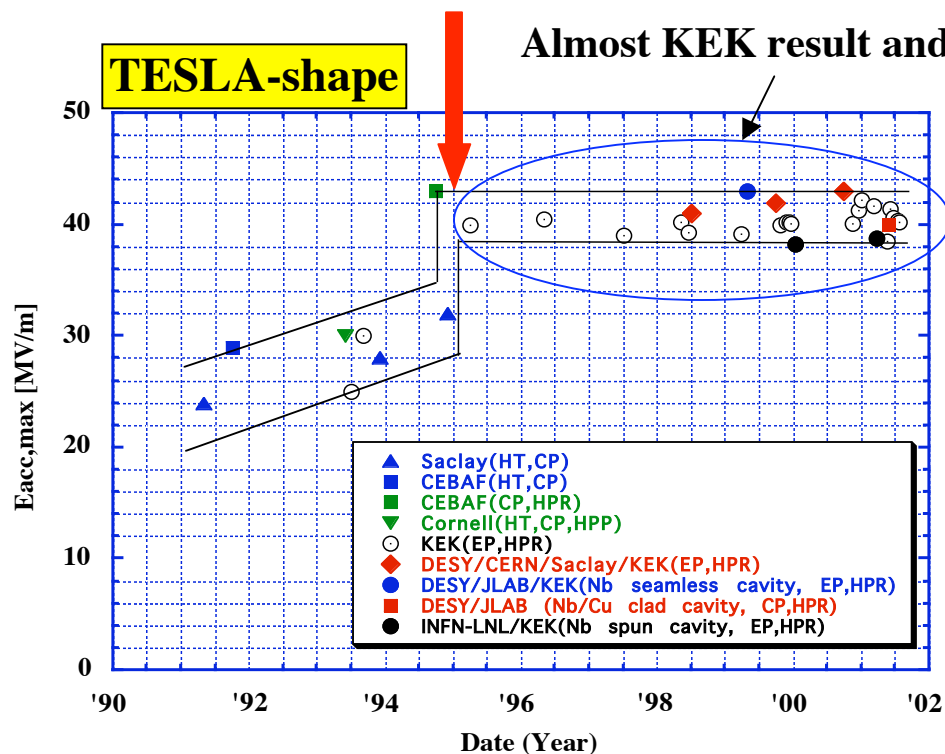
$$H_c^{\text{Line}} = \frac{\xi}{\lambda} H_c = \frac{H_c}{\kappa}$$



High Gradient Limitation of Type-II SRF cavities

HPR

Saito thesis : SRF Workshop 2001



$$H_{cr}(T) = \frac{\xi(T)}{\lambda(T)} \cdot \sqrt{2}H_c(T) = \frac{\sqrt{2}H_c(T)}{\kappa(T)} = \sqrt{2} \frac{H_c(0)}{\kappa(0)} \cdot \left[1 - \left(\frac{T}{T_c} \right)^4 \right] \quad H_{cr}^{Nb}(t) = 1750 \cdot [1 - t^4]$$

Eacc ~ 50 MV/m is still reachable if one changes cavity shape with a smaller Hp/Eacc (= 35 Oe / [MV/m]) ratio.

Which material is best ?

Material point of view:

- Smaller heat loading for refrigerator → **Higher T_c**

- High gradient

$H_{RF} > H_c^{RF}$, then normal conducting

$$H_c^{RF} = \sqrt{2} \cdot \frac{H_c}{\kappa}, \quad \kappa : G - L \text{ parameter}$$

The material with higher H_c and smaller κ -value

If H_c is high enough, Type-I material is better because of the smaller κ -value.

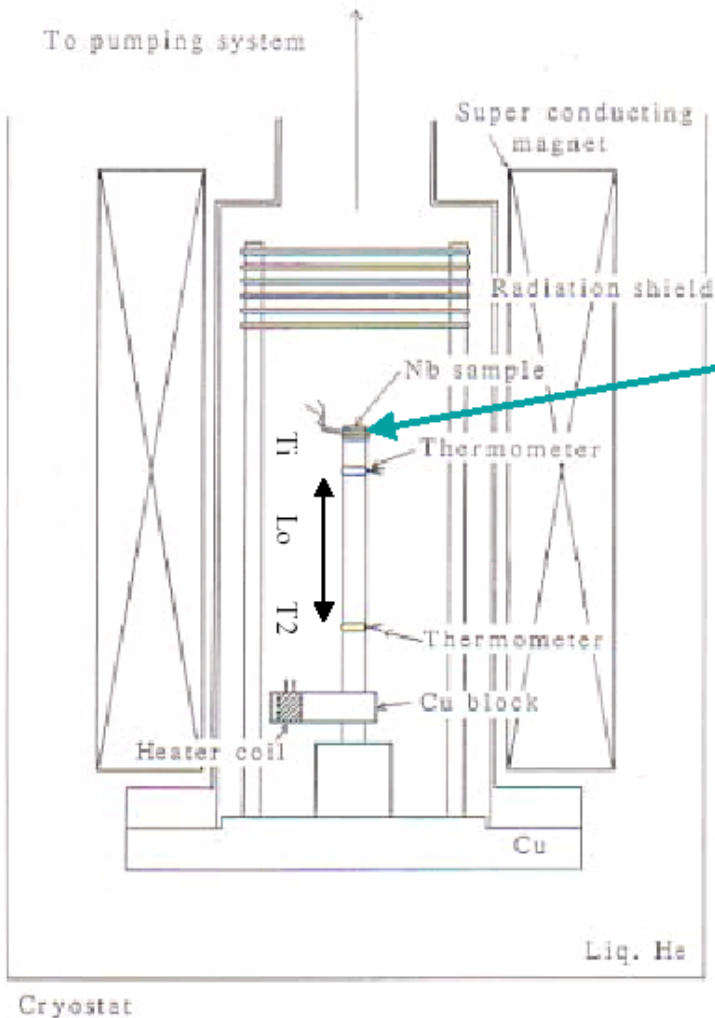
- Good formability

Materials	T_c [K]	H_c, H_{c1} [Gauss]	κ	Type	Fabrication
Pb	7.2	803, -	0.65	I	Electroplating
Nb	9.25	1900, 1700	1.5	II	Deep drawing, film
Nb ₃ Sn	18.2	5350, 300	7	II	Film
MgB ₂	39	4290, 300		II	Film

**Niobium has higher T_c , H_c and enough formability.
Now, niobium is widely used for RF sc cavity production.**

Q4: Thermal Conductivity in Superconducting State and Residual Resistance Ratio (RRR)

Thermal conductivity measurement



Normal conductor : $\kappa_{en} = \frac{1}{W_{en}} = \left[\frac{\rho}{L_0 T} + aT^2 \right]^{-1}$

$\rho = \frac{\rho_{300K}}{RRR}$ e-impurities scatt.
e-lattices scatt.

Wiedemann-Franz law:

$\kappa_e = \frac{\pi^2 n k_B^2 \tau}{3m} \cdot T$, $\frac{\kappa_e}{\sigma} = \frac{\pi^2}{3} \left(\frac{k_B}{e} \right)^2 \cdot T = L_0 T$

$$P[w] = S(m^2) \cdot \kappa(T) \cdot \frac{T_1(K) - T_2(K)}{L_0(m)}$$

$$T \equiv \frac{T_1 + T_2}{2}, S: \text{ area of cross - section}$$

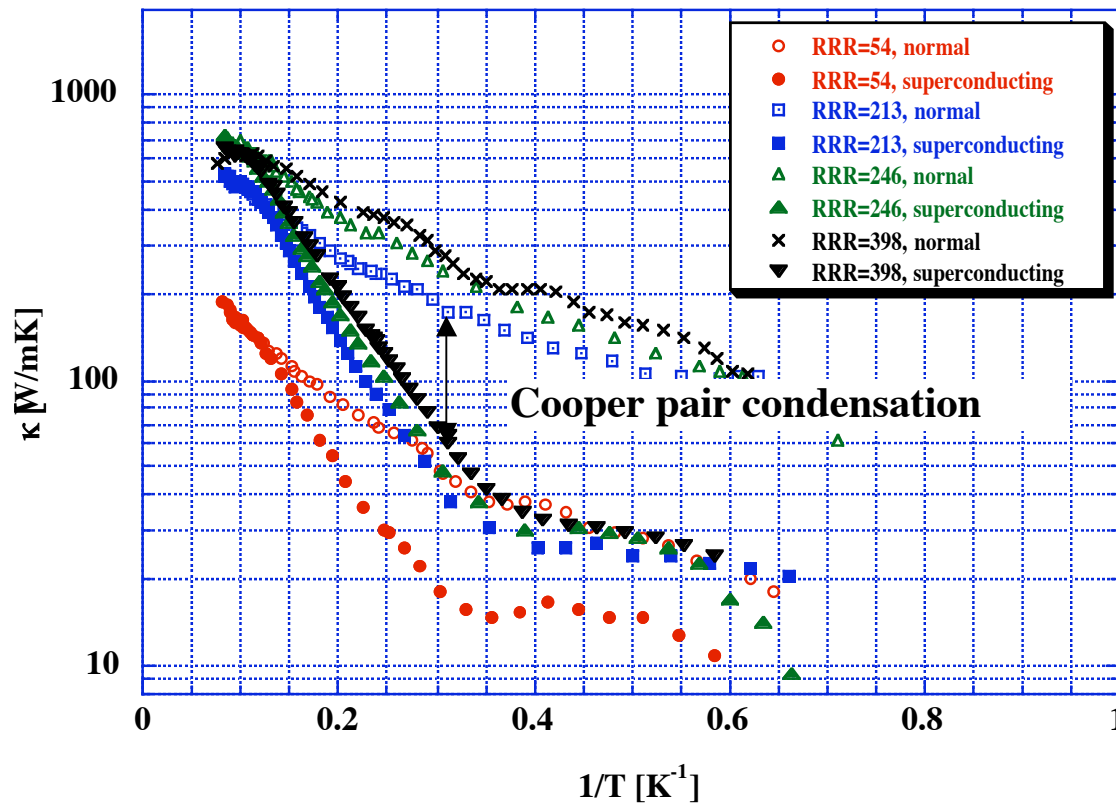
$$\kappa(T) = \frac{P}{S} \cdot \frac{L_0}{T_1 - T_2} \quad \left[\frac{w}{m \cdot K} \right]$$

Thermal conductivity of Nb material at low temperature

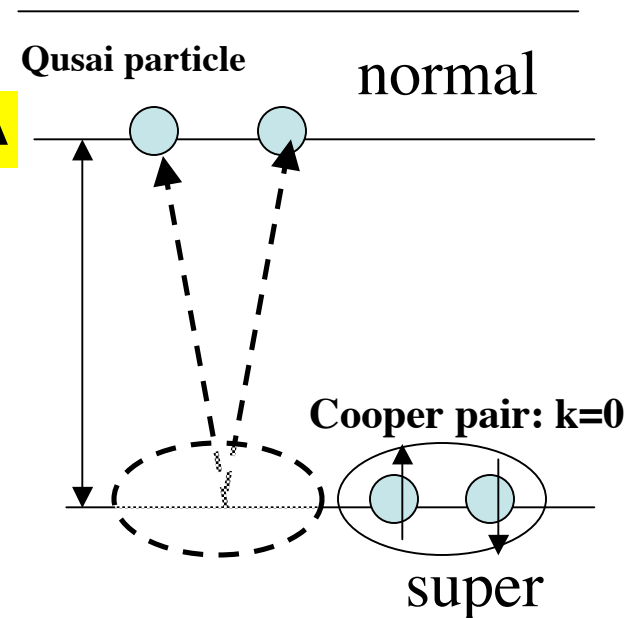
Boltzmann statistics : energy Δ , Temp.

Excitation probability @T and energy Δ

$$\exp\left(-\frac{\Delta}{k_B \cdot T}\right)$$



2Δ



Calculation of thermal conductivity based on Quantum mechanics

$$\kappa_s(T) = R(y) \cdot \left[\frac{\rho_{295K}}{L \cdot RRR \cdot T} + a \cdot T^2 \right]^{-1} + \left[\frac{1}{D \cdot \exp(y) \cdot T^2} + \frac{1}{BlT^3} \right]^{-1}$$

ρ_{295K} : e - impurities scatt.
 a : e - phonons scatt.
 D : lattice - phonons scatt.
 BlT^3 : lattice - grain boundaries scatt.

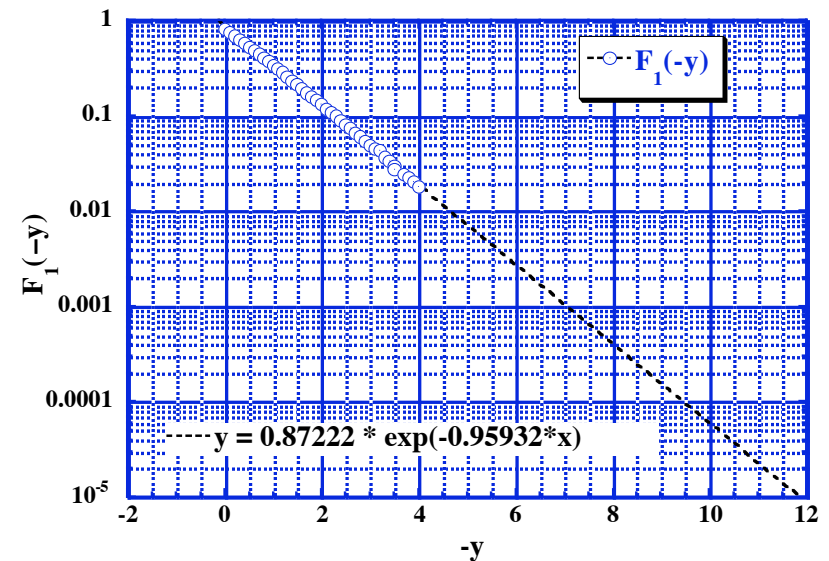
$$L = 2.05E - 8, RRR = 200, \rho_{295K} = 14.5E - 8 \Omega m, a = 7.52E - 7$$

$$-y = \alpha \cdot \frac{T_c}{T}, \alpha = 1.53, T_c = 9.25K, T \leq 0.6 \cdot T_c$$

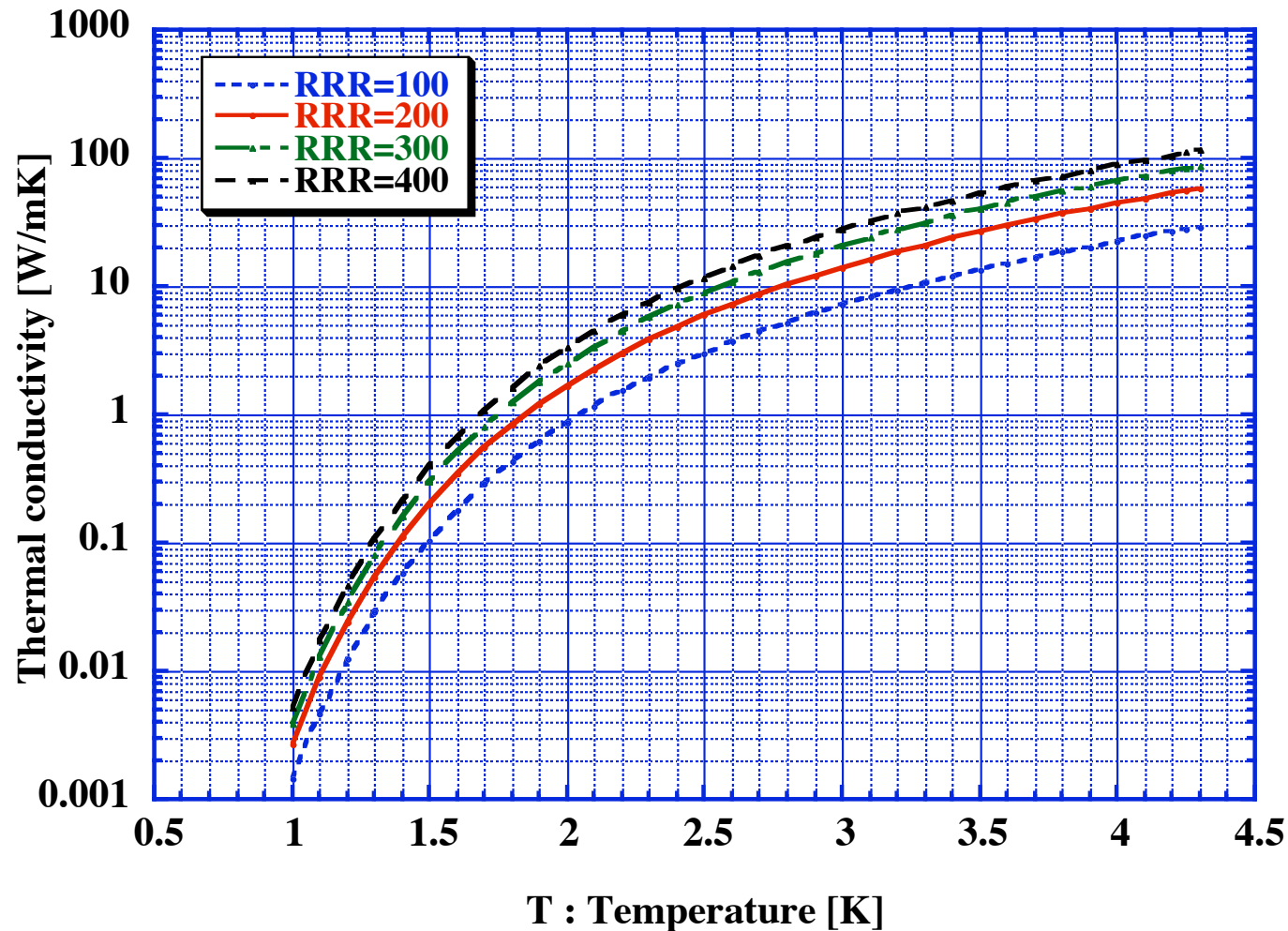
$$D = 4.27E - 3, B = 4.34E 3, l = 50\mu m$$

$$R(y) = \frac{\kappa_{es}}{\kappa_{en}} = \frac{2F_1(-y) + 2y \ln(1 + e^{-y}) + \frac{y^2}{(1 + e^y)}}{2F_1(0)},$$

$$F_n(-y) = \int_0^\infty \frac{z^n}{1 + e^{z+y}} dz$$



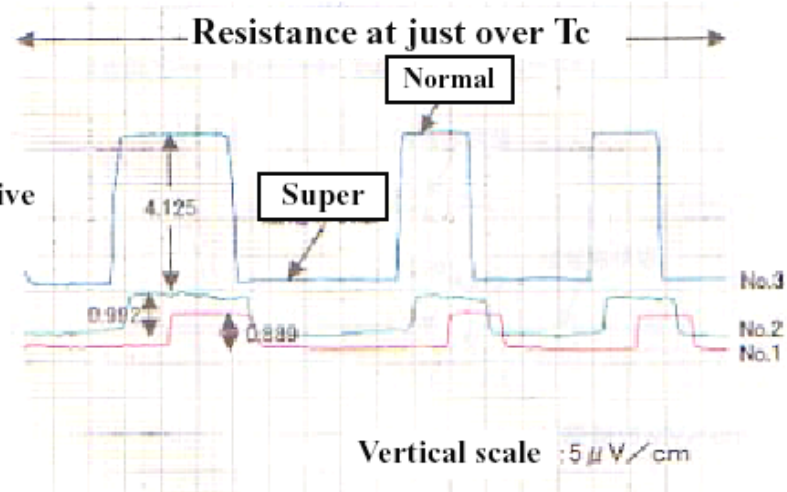
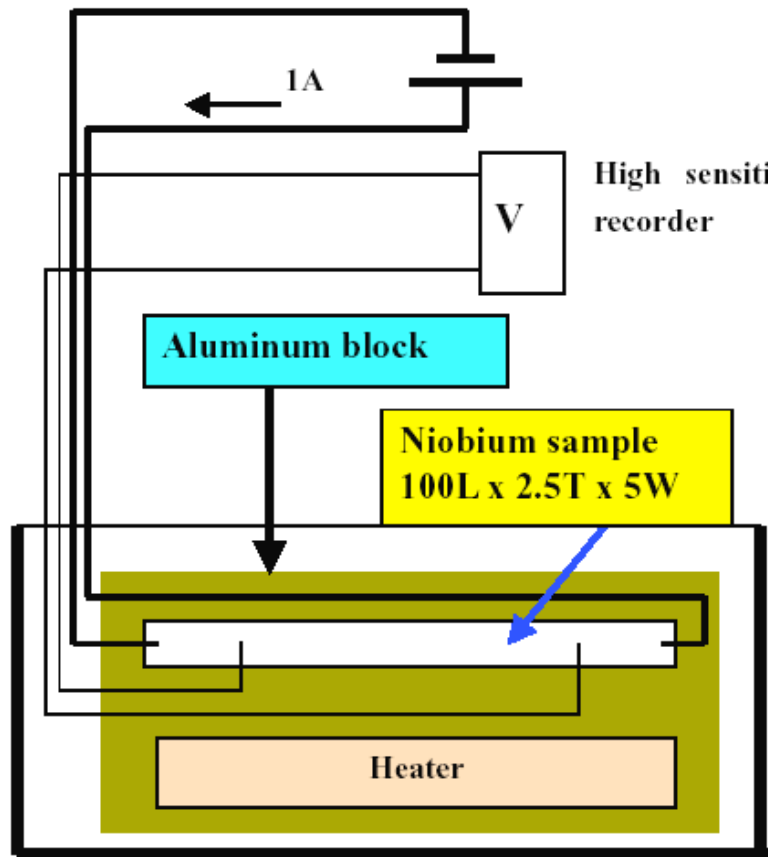
Calculated $\kappa_{sc}(T)$



Thermal conductivity at 2K with Nb is $\sim 1/15$ of that of stainless at room. Temp.(15W/m*K) or $1/6800$ of that of copper at 4.2K (6800W/m*K).

RRR measurement

Very simple measurement !!



$$\kappa(T) \propto RRR$$

$$RRR \equiv \frac{R(300\text{K})}{R(9.5\text{K})}$$

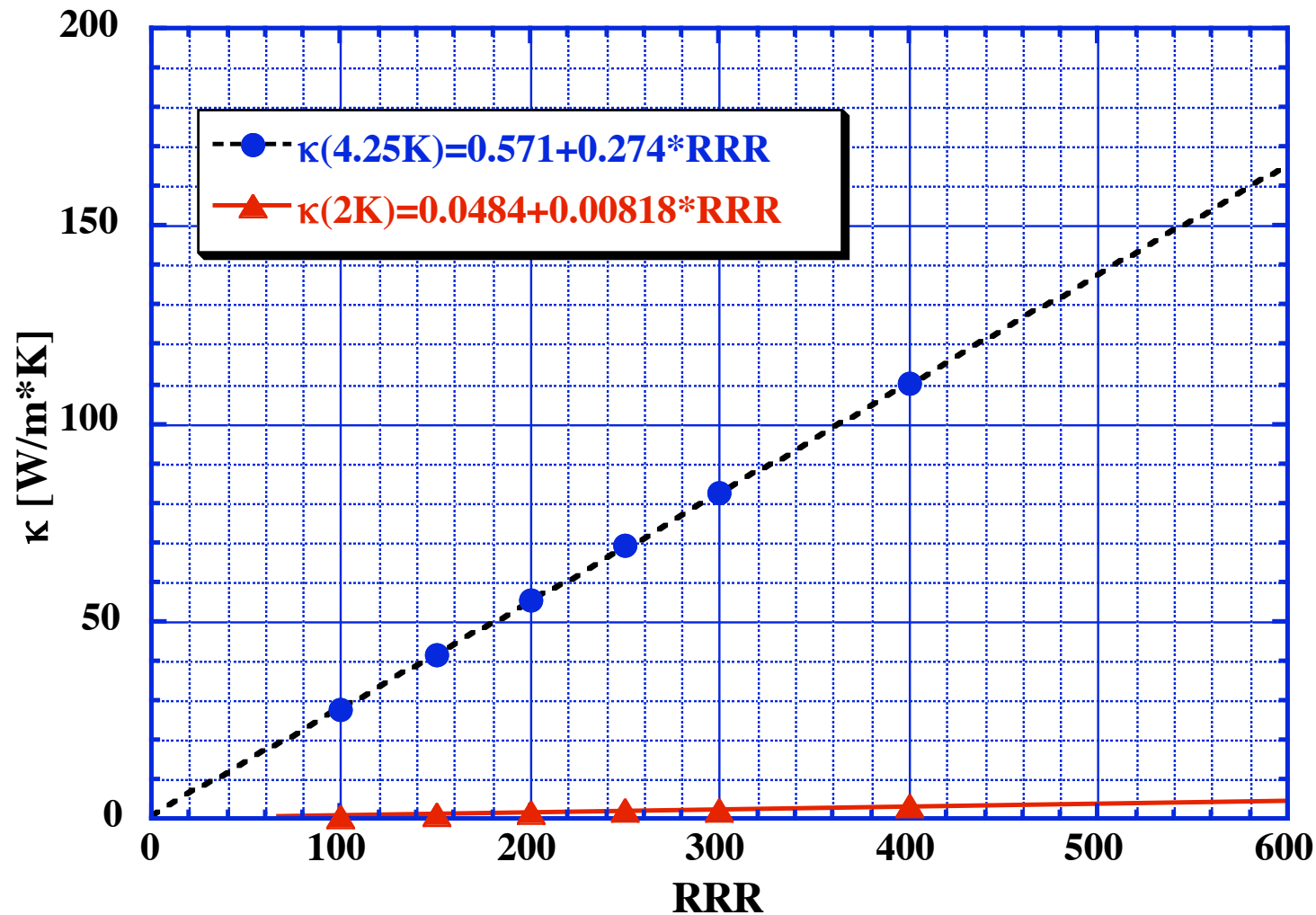
$$\frac{1}{RRR} = \sum_{\text{elements in Nb}} \frac{C(i)}{\rho(i)} = \frac{C_H}{1500} + \frac{C_C}{4100} + \frac{C_N}{3900} + \frac{C_O}{5000} + L + \frac{C_{Ta}}{550000}$$

Example:

$$C_H = 1\text{ppm}, C_C = 5\text{ppm}, C_N = 5\text{ppm}, C_O = 7\text{ppm}, C_{Ta} = 400\text{ppm} \quad (99.9582\%)$$

$$RRR = 188.8$$

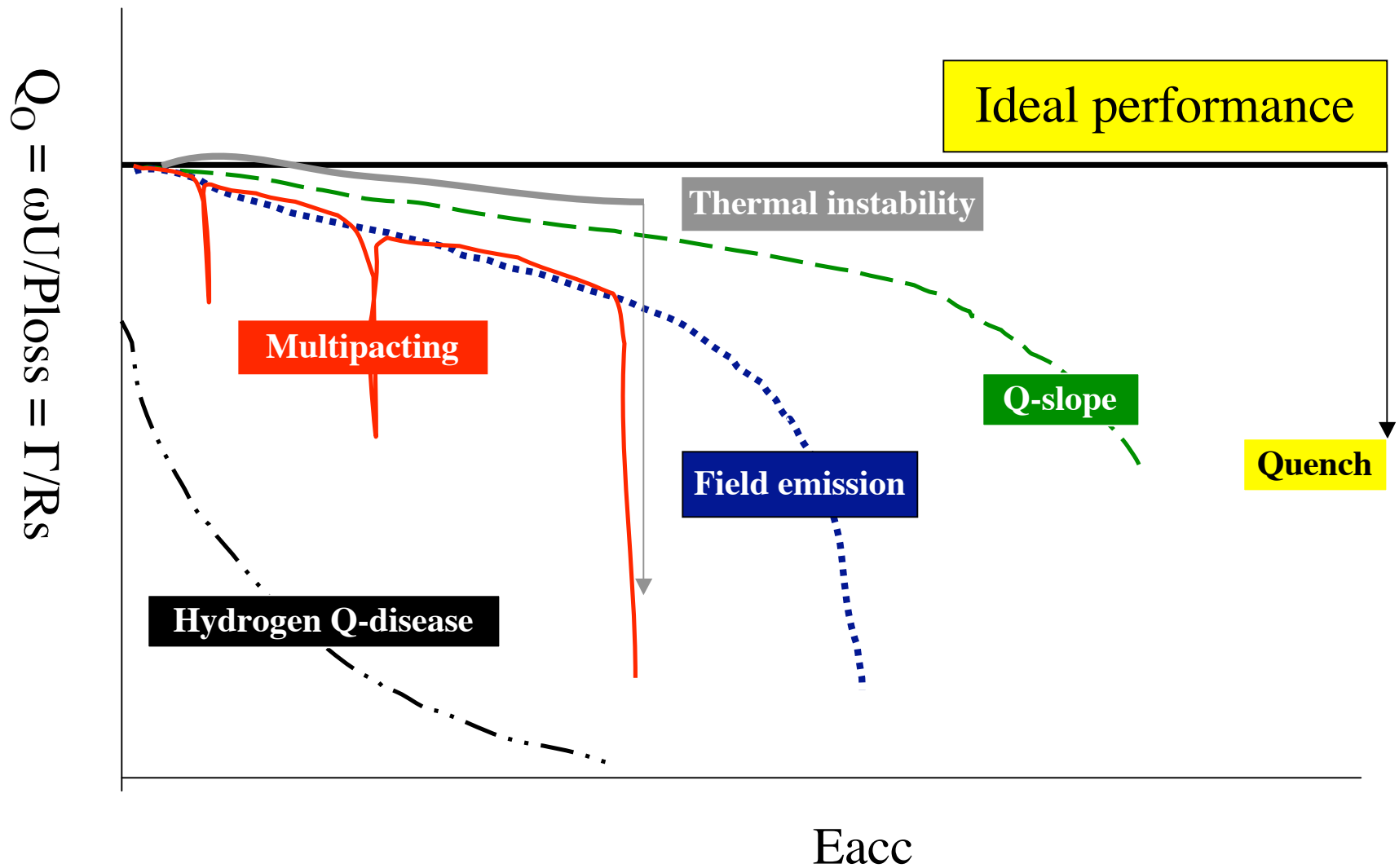
Linear relationship between κ_{SC} (2K, 4.25K) and RRR



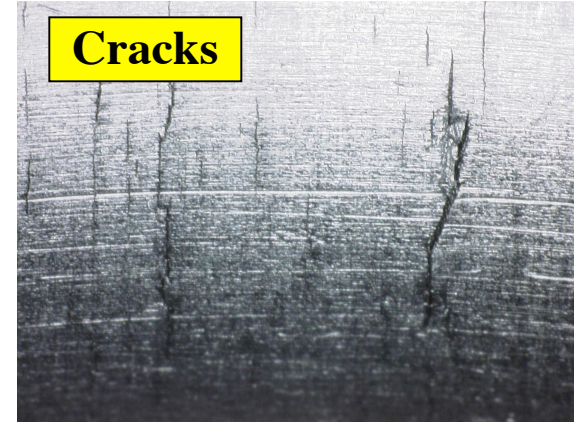
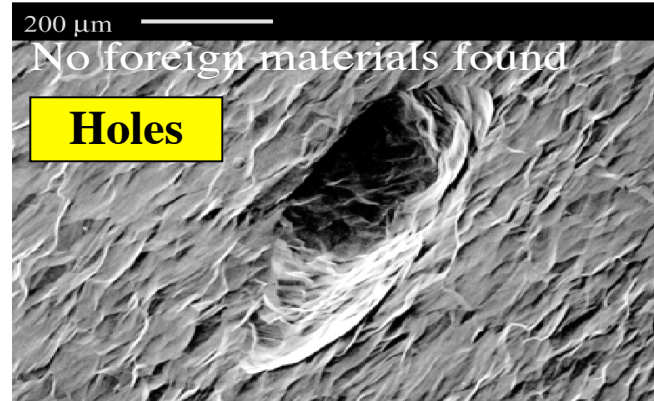
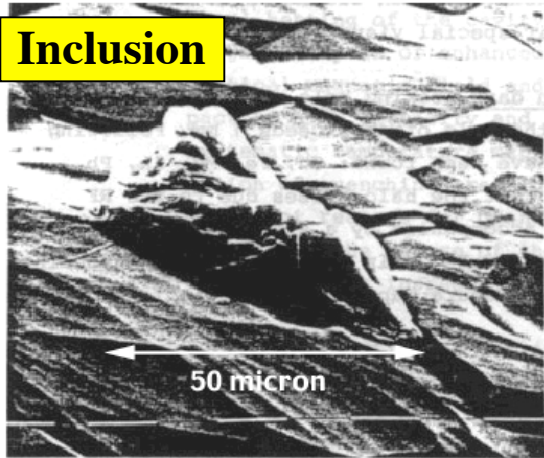
RRR is a good parameter to evaluate thermal conductivity of superconductor.

Q5: Real SRF field limitation and Technologies to push gradient

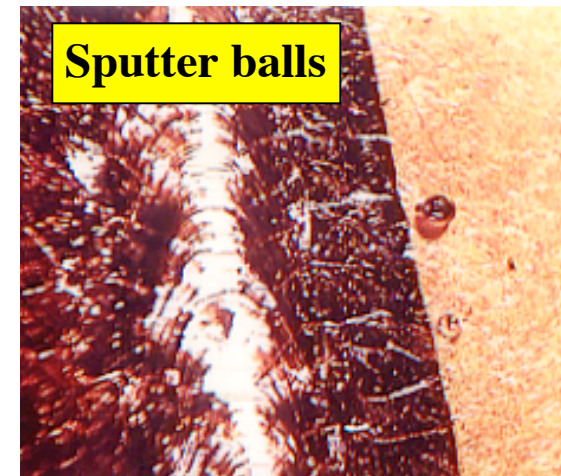
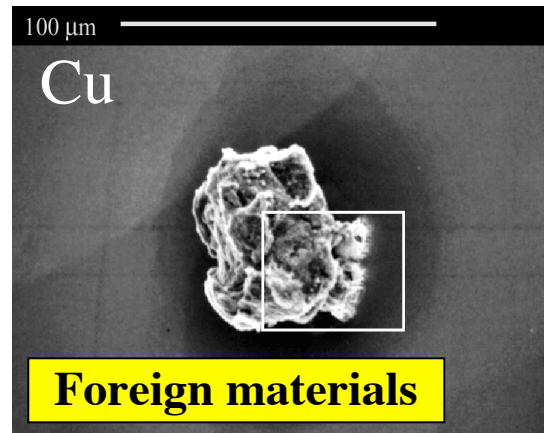
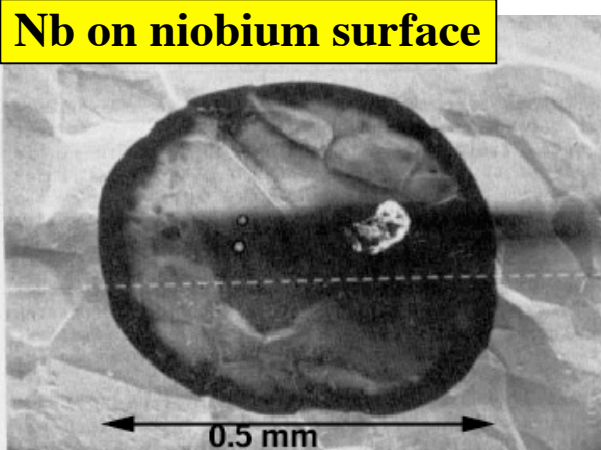
Real SRF Cavity Performance



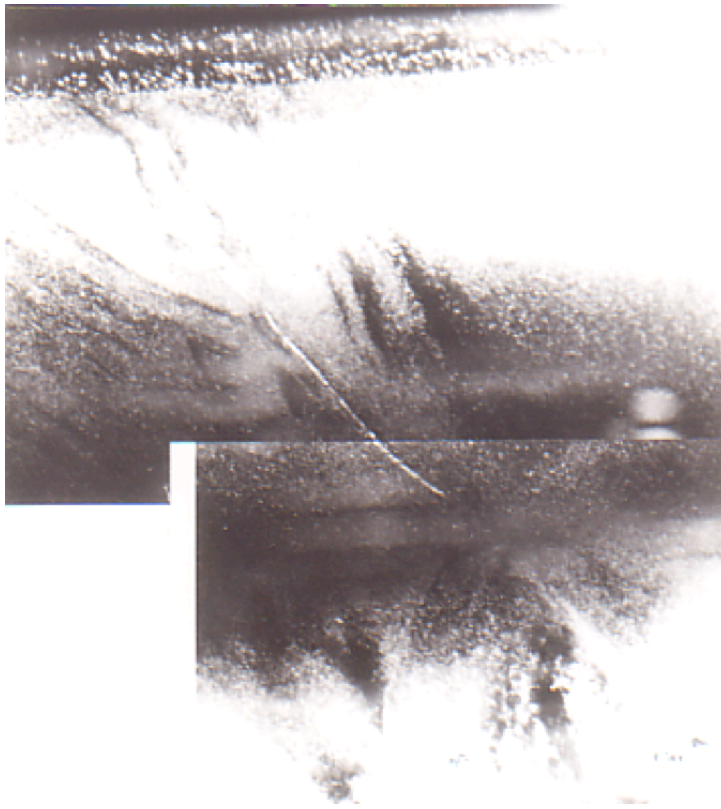
Various Surface Defects



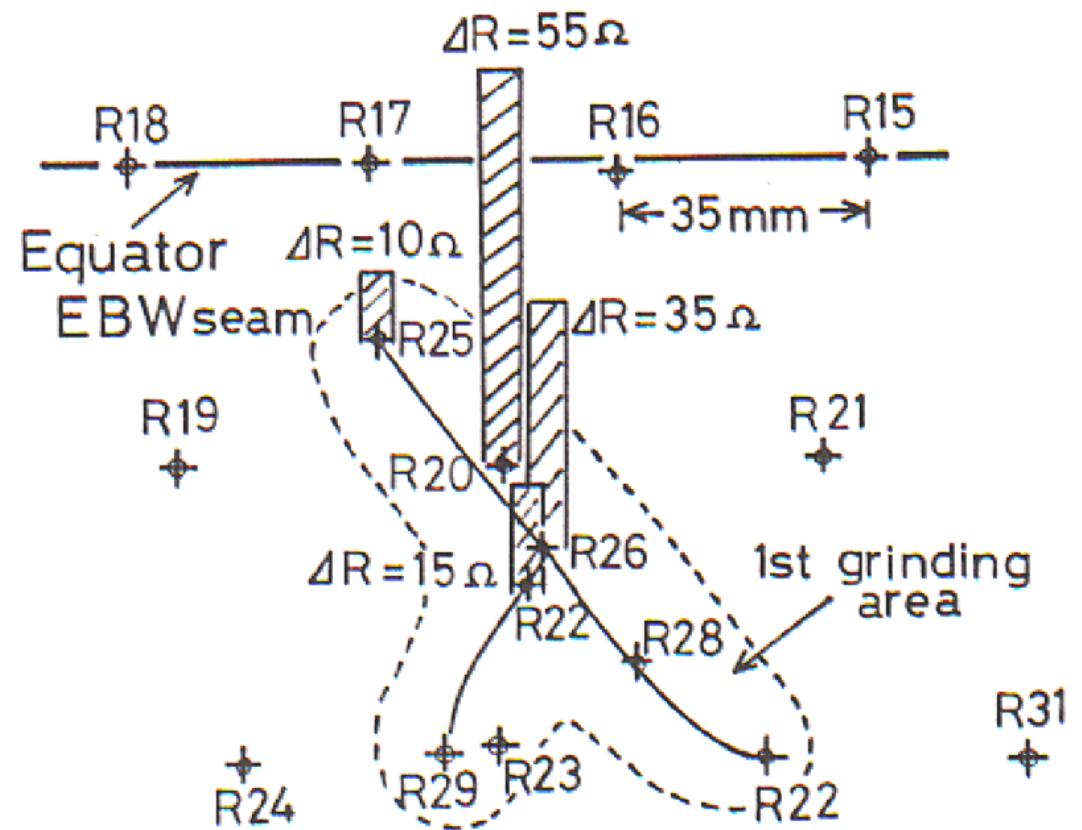
Surface defects, holes can also cause TB



Surface Defect

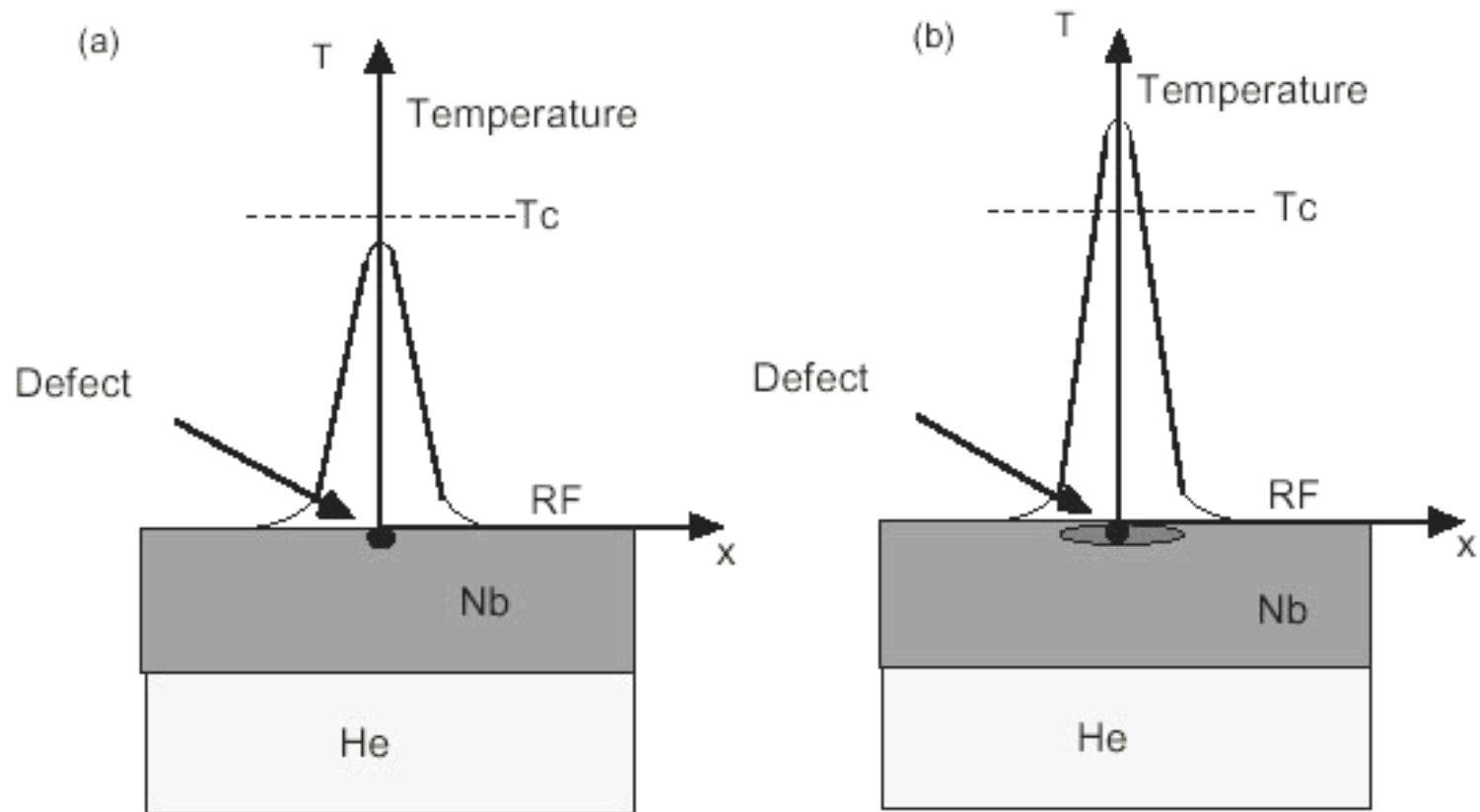


Picture of the defect area



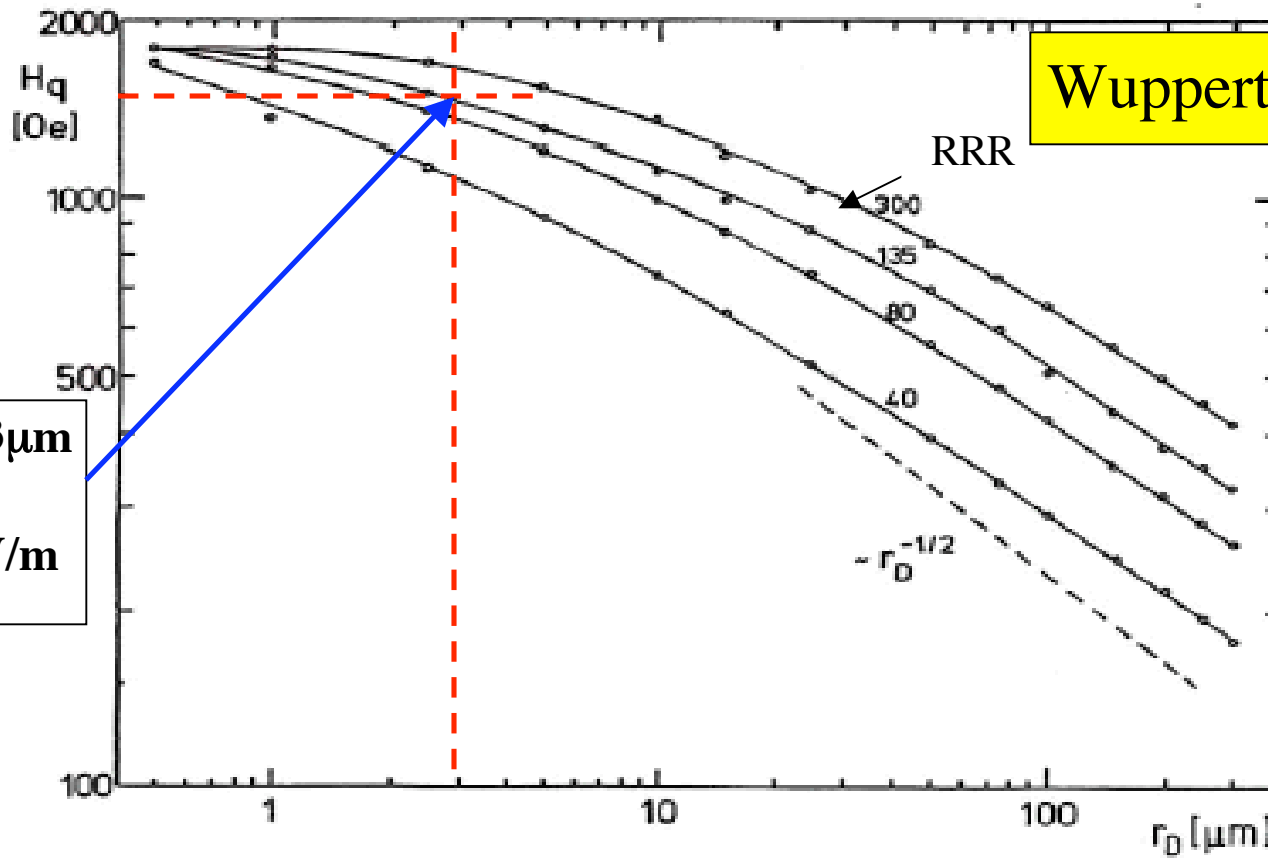
T-mapping on the defect

Mechanism of Thermal Instability



RRR Dependence of Quench Field

$$\text{Quench Field : } H_q = \sqrt{\frac{4\kappa(T_c - T_b)}{r_D \cdot R_s(T_b)}} \propto RRR^{\frac{3}{4}} \cdot \sqrt{\frac{(T_c - T_b)}{r_D \cdot R_s(300K)}}$$



RRR=135 at $r_D=3\mu\text{m}$
 $H_q \sim 1500\text{Oe}$
 $E_{acc,max} \sim 34\text{MV/m}$

Defect radius

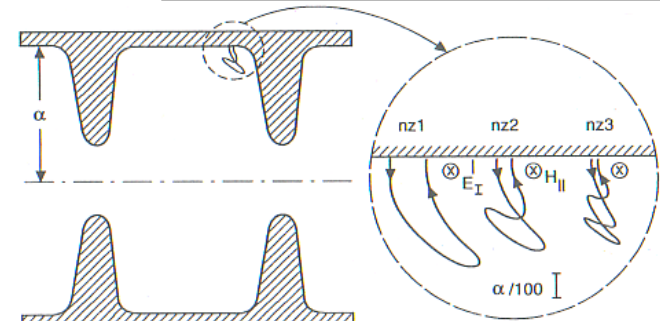
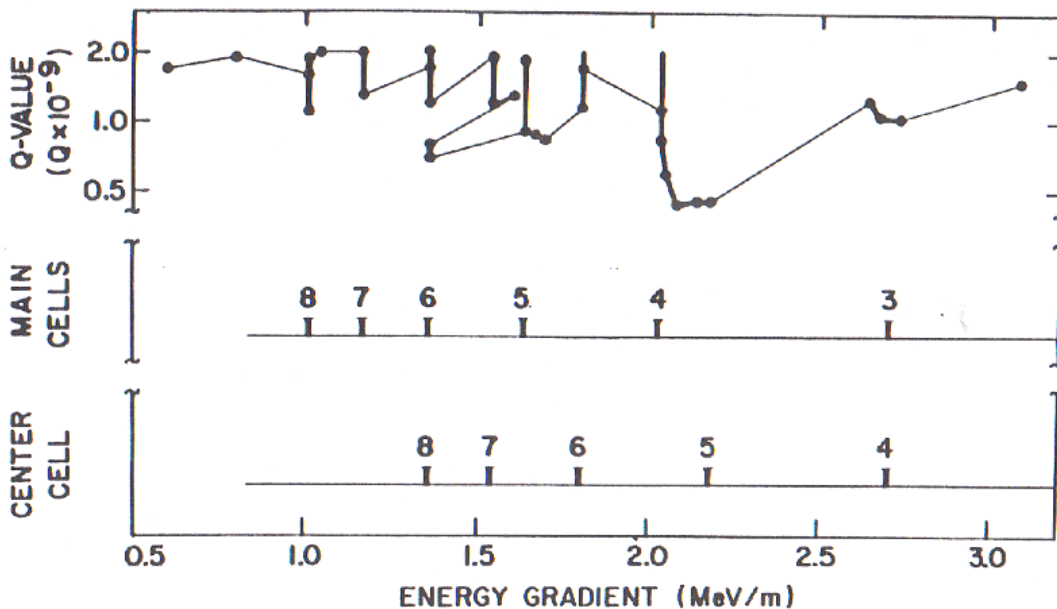
Needs control the defects with 1mm size, Use high pure niobium material with $RRR > 200$

Multipacting

Multipacting : Resonant electron loading due to secondary electrons
 (synchronized electron motion with RF)

Limited the performance by
 1PM or 2PM.

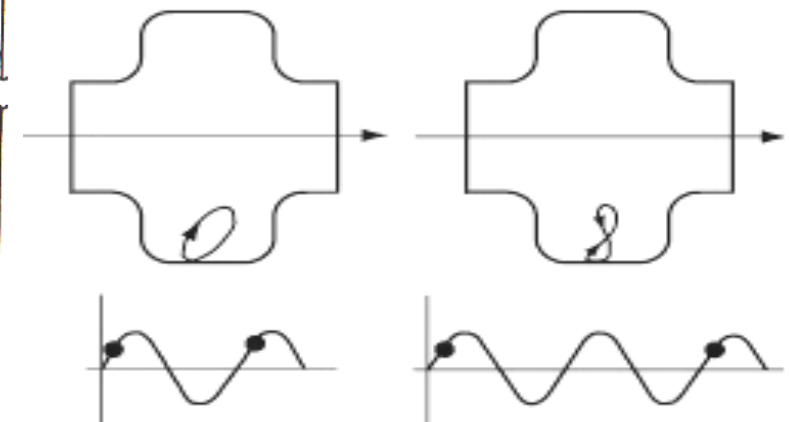
One point multipacting



1 point MP

1st Order

2nd Order



Characteristic: Q-drop at some discrete field levels, X-ray at the levels,
Diagnostics: Temperature mapping & X-ray mapping

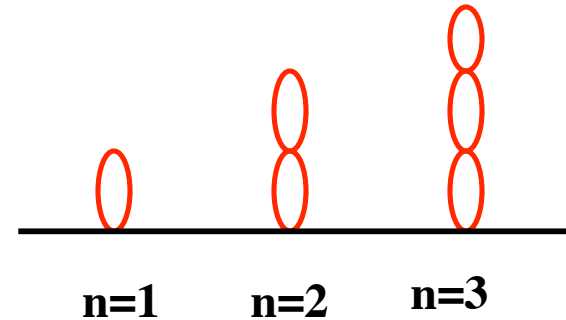
Onset Field of One-point MP

Scale law on RF frequency with the multipacting levels

$$\text{Cyclotron frequency : } \omega = \frac{e \cdot H}{c \cdot m}$$

$$2\pi \cdot f(1P - nth) = \frac{e \cdot H(1P - nth)}{c \cdot m},$$

$$T(1P - nth) = \frac{1}{f(1P - nth)} = \frac{2\pi \cdot c \cdot m}{e \cdot H(1P - nth)} = n \cdot T_{RF} = \frac{n}{f_{RF}}$$



$$\frac{H(1P - nth)}{f_{RF}} = \frac{\text{constant}}{n}, \quad n=1, 2, 3 \dots \quad [\text{Oe/Hz}]$$

Experiment : Onset field $\frac{H(1P - nth, [\text{Oe}])}{f_{RF} [\text{MHz}]} = \frac{0.3}{n} \quad [\text{Oe/MHz}]$

Spherical shape suppresses the one point multipacting.

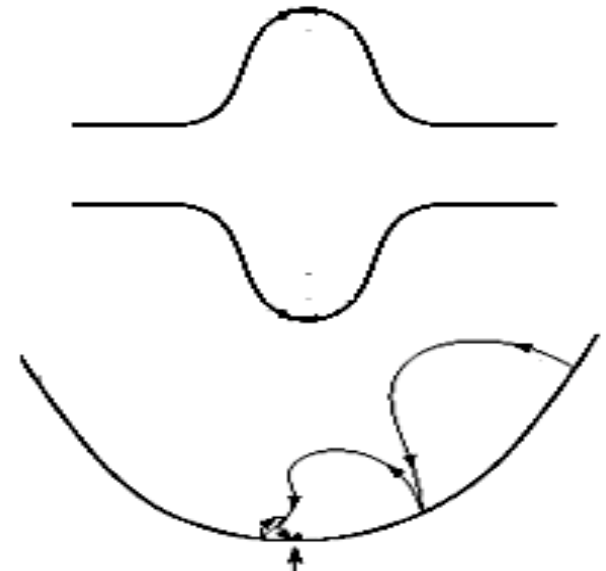
Example ;

1300MHz, $H_p/E_{acc} = 43.8 [\text{Oe}/(\text{MV}/\text{m})]$

1P-1st order $\cdot \cdot \cdot H_{RF}(1P-1^{st}) = 0.3 \times 1300 = 390 \text{ Oe}$

$E_{acc}(1P-1^{st}) = 390/43.8 = 8.9 \text{ MV}/\text{m}$

1P-2nd order $\cdot \cdot \cdot E_{acc}(1P-2^{nd}) = 4.5 \text{ MV}/\text{m}$



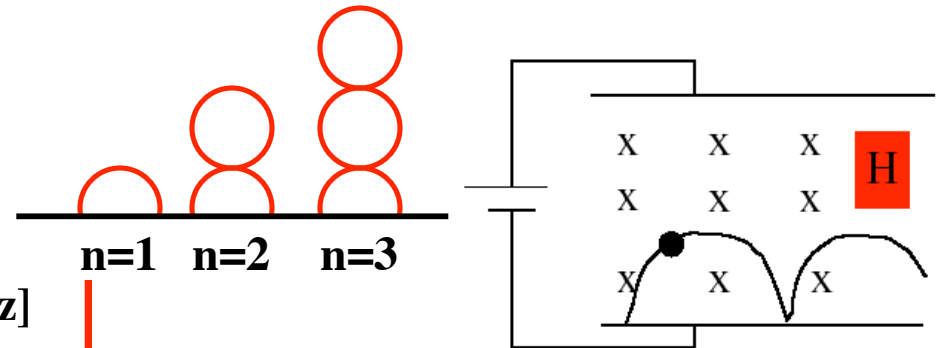
Two-point MP

Two-point multipacting

$$T(2P - nth) = (2n - 1)T_{RF}$$

$$\frac{H(2P - nth)}{f_{RF}} = \frac{\text{constant}}{2n - 1}, n=1, 2, 3 \dots [\text{Oe/Hz}]$$

$$\text{Experiment : Onset field} \quad \frac{H(2P - nth, [\text{Oe}])}{f_{RF} [\text{MHz}]} = \frac{0.6}{2n - 1}$$



Examples ;

508MHz , Hp/Eacc=40.6 [Oe/(MV/m)]

2P-1st order Hp(2p-1st) = 0.6 x 508 = 304.8 Oe

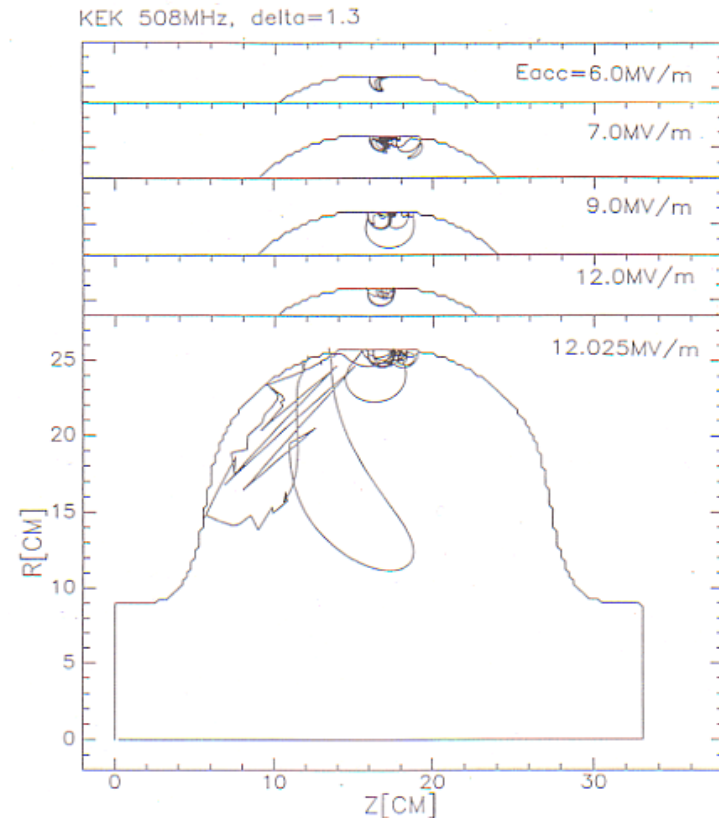
Eacc(2P-1st) = 304.8/40.6 = 7.5 MV/m

1300MHz, Hp/Eacc=43.8 [Oe/(MV/m)]

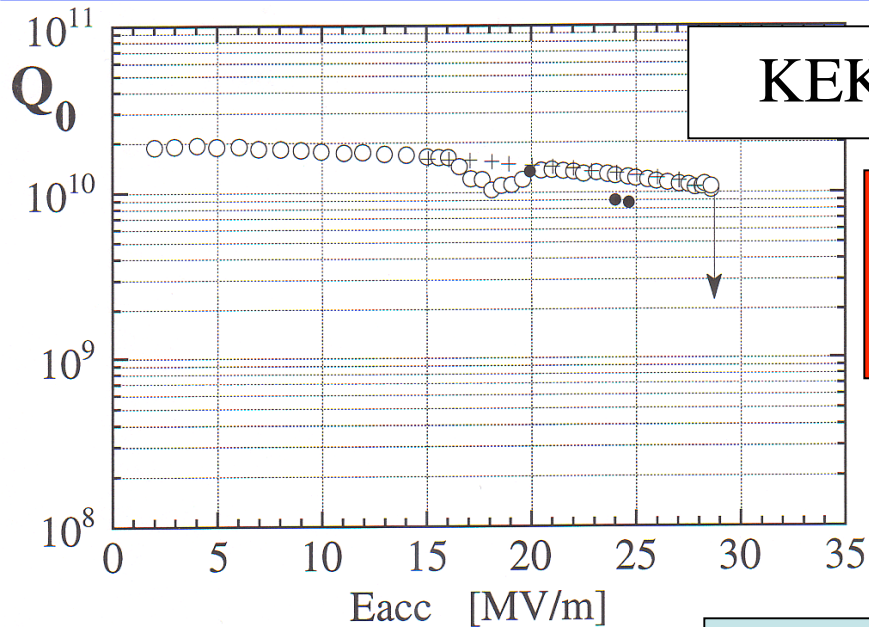
2P-1st order Hp(2p-1st) = 0.6 x 1300 = 780 Oe

Eacc(2P-1st) = 780/43.8 = 17.8 MV/m

2P-2nd order Eacc(2P-2nd) = 17.8/3 = 5.9 MV/m

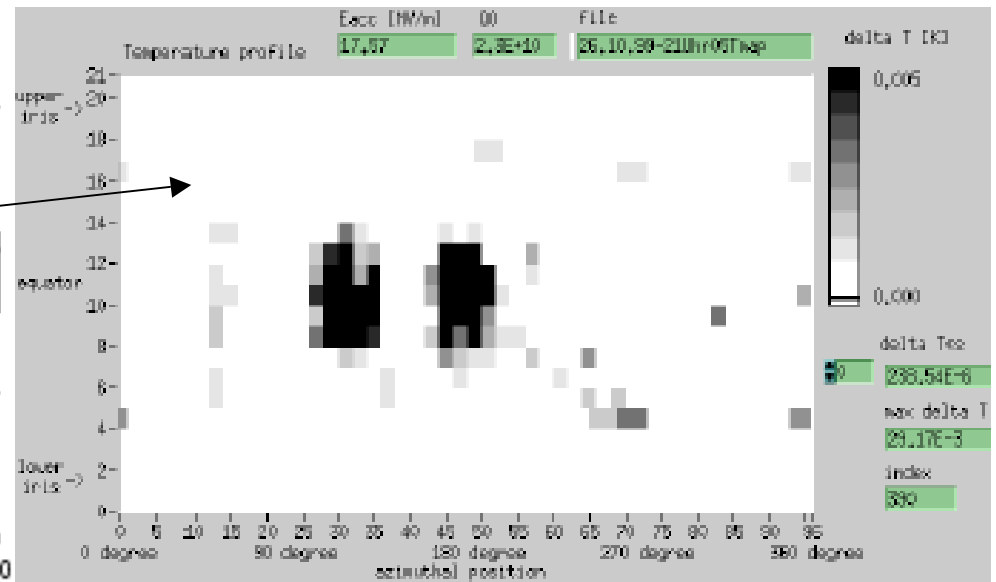
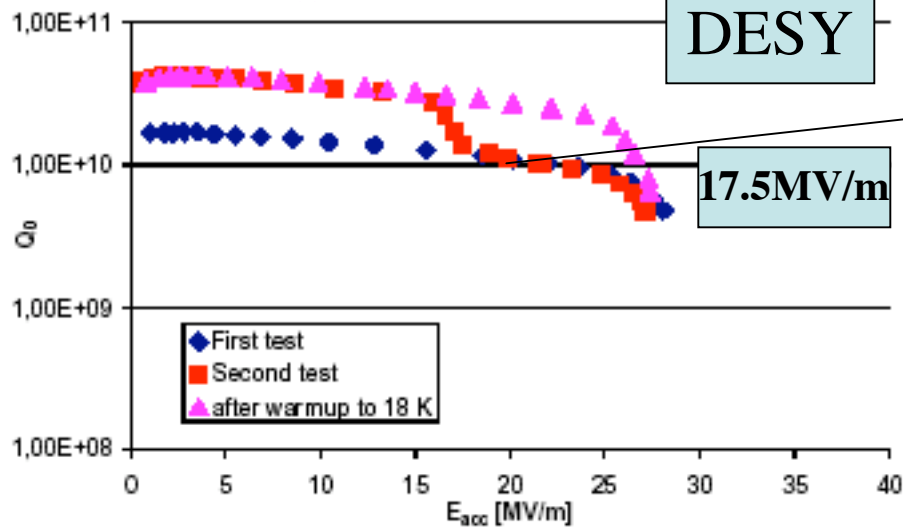


T-mapping of Tow-point MP



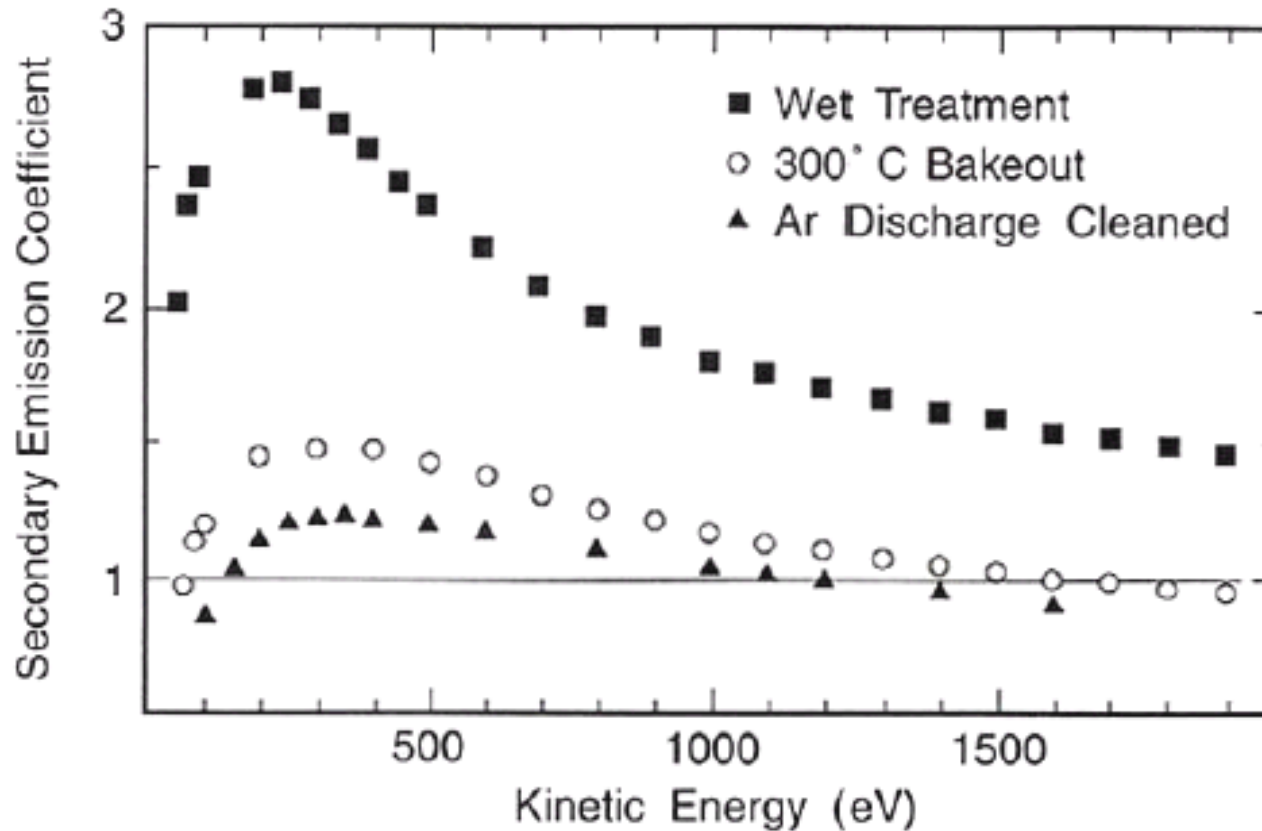
MP \rightarrow Frozen flux trapping \rightarrow Warm-up $T > T_c$
 \downarrow
 Disappear of the heating spots

T-mapping at 17.5MV/m



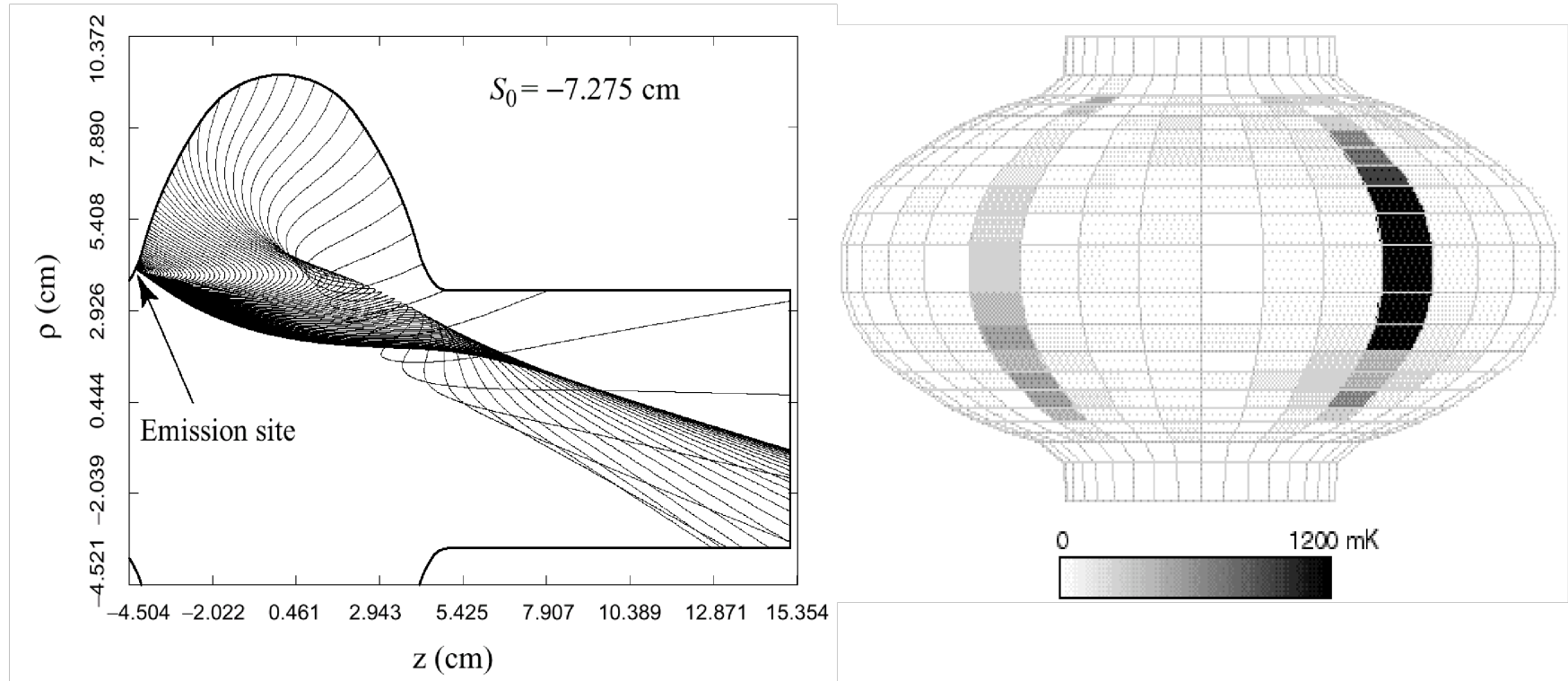
Cures against MP

- 1) Cavity shape \longrightarrow Spherical or Elliptical shape
(effective for one point multipacting)
- 2) $\delta < 1$: Clean surface \longrightarrow Surface preparation
High pressure water rinsing
Argon gas or Helium gas discharge cleaning



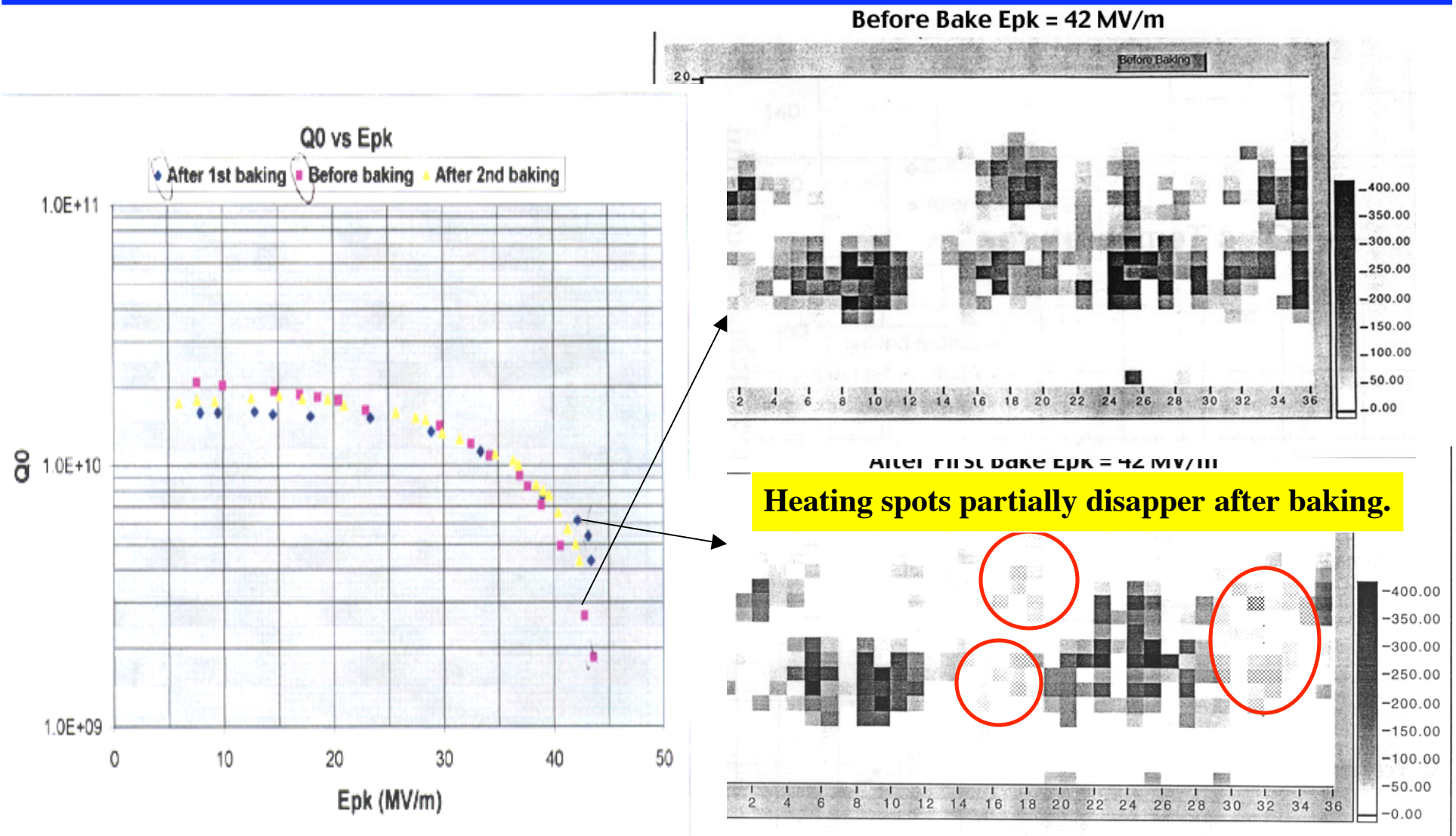
Field Emission

Non-resonant electron loading due to field emitted electrons by tunneling effect

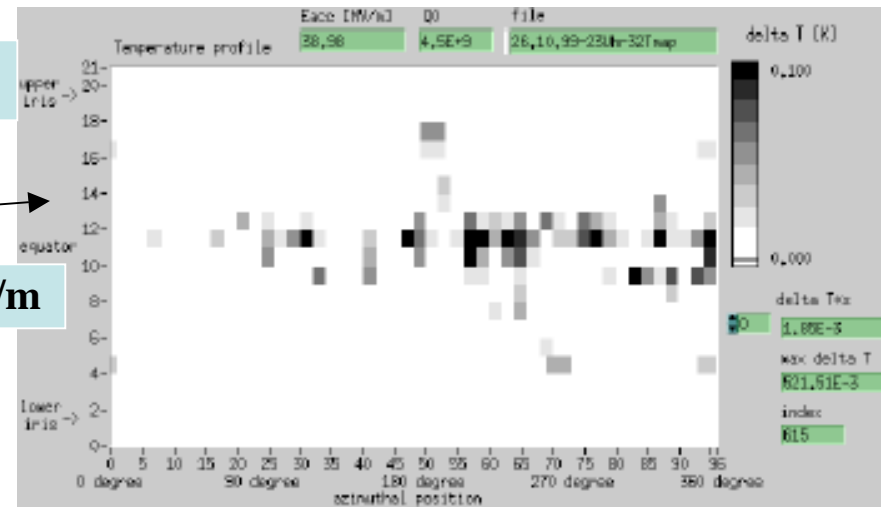
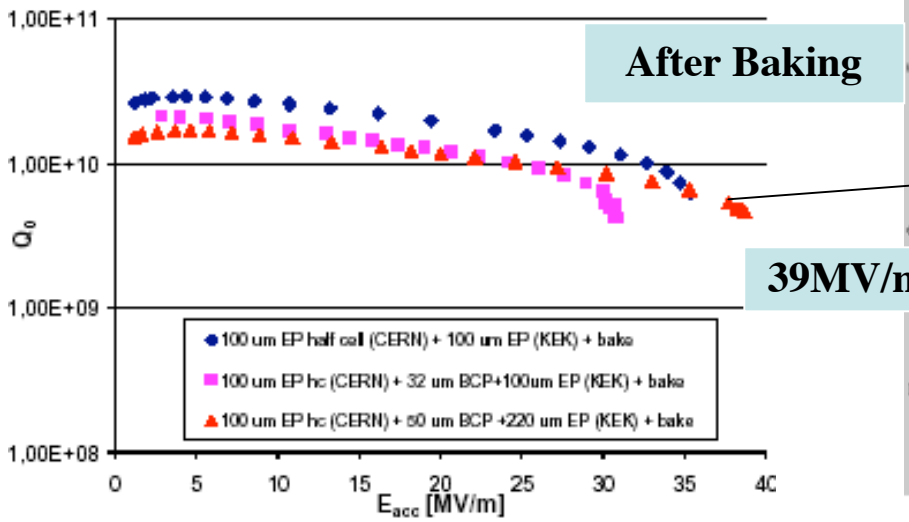
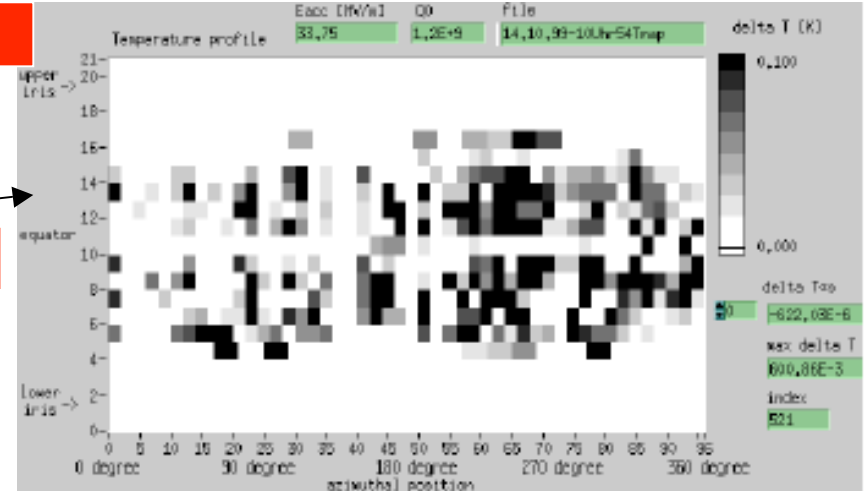
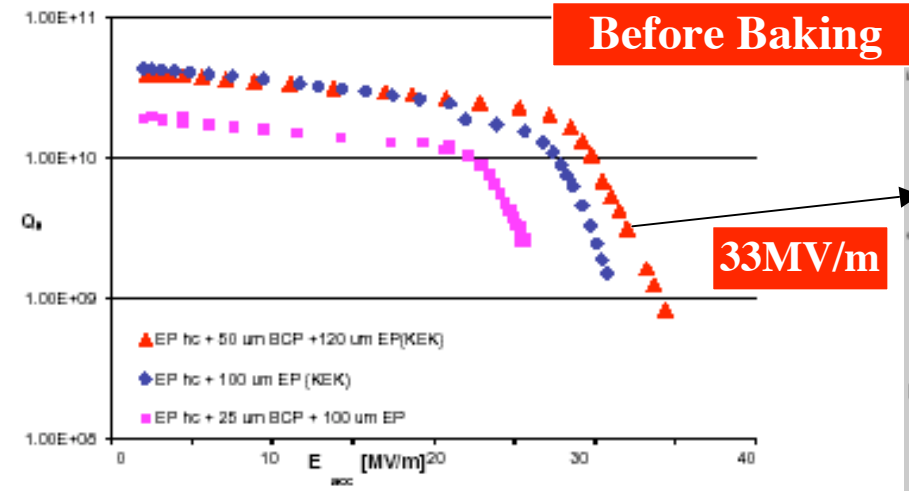


Heating on meridian

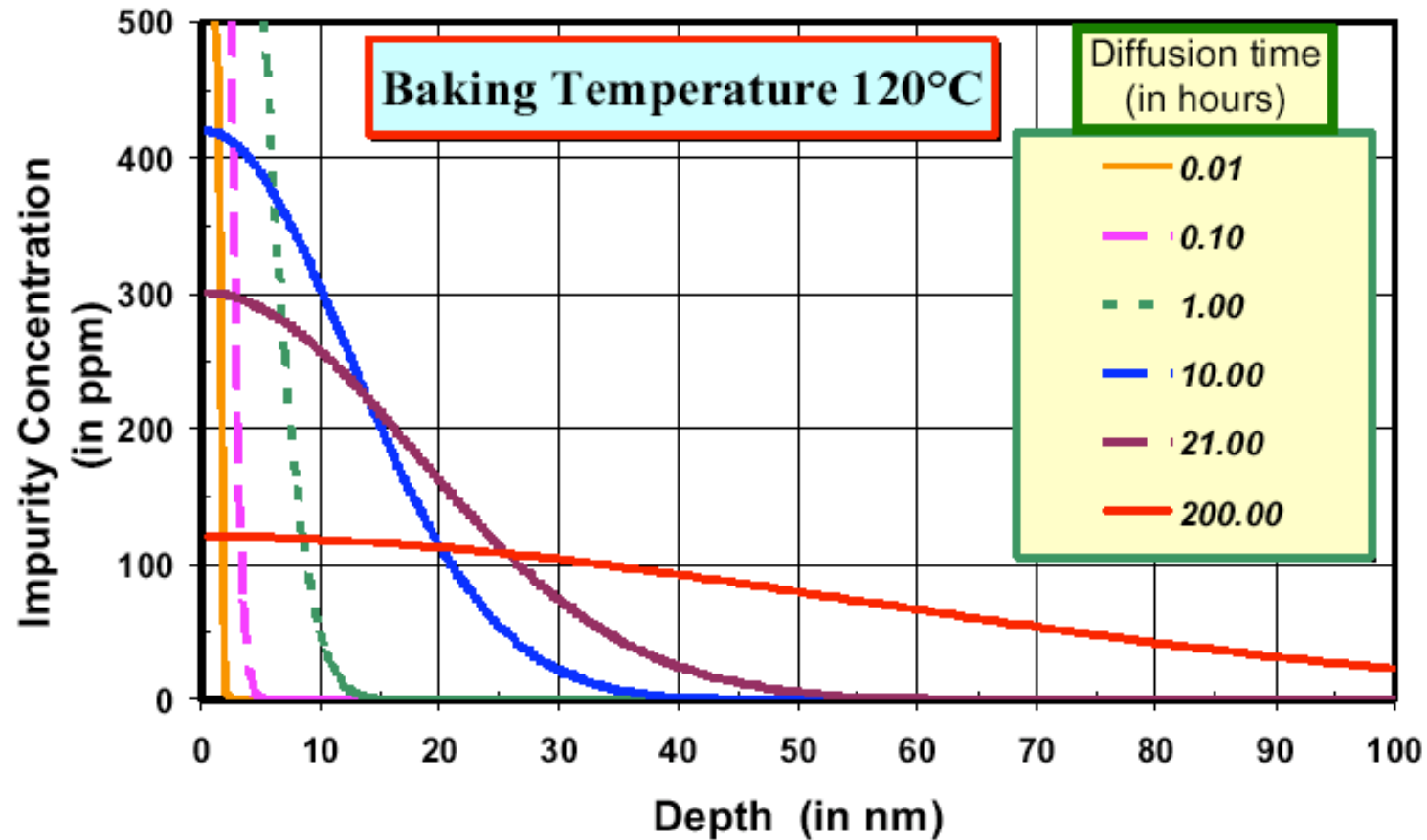
Q-slope: Partially Disappeared Heating Spots by Baking on CP Cavity



Q-slope: Disappeared Heating Spots by Baking on EP Cavity



Oxygen Diffusion



Oxygen on top diffuse into bulk by baking (120°C for 48 hr).

Loss Mechanism

Interface Tunnel Exchange (ITE Model) By J. Halbritter

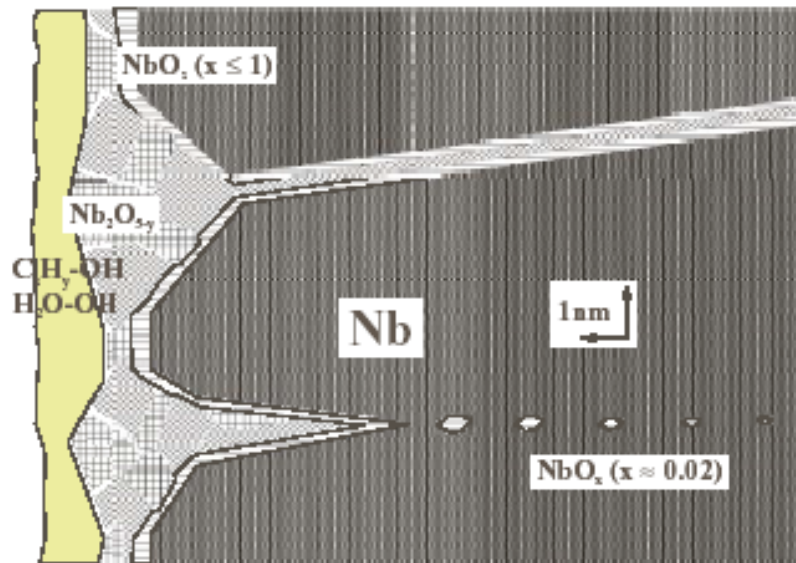


Fig. 1: Nb surface with crack corrosion by oxidation by Nb_2O_5 volume expansion (factor 3). $\text{Nb}_2\text{O}_{5-y}$ - NbO_x weak links/segregates ($y, x < 1$) extend up to depths between $0.01 - 1/1-10 \mu\text{m}$ for good - bad Nb quality and weak - strong oxidation [8]. Embedded in the adsorbate layer of $\text{H}_2\text{O}/\text{C}_x\text{H}_y\text{OH}$ ($\geq 2 \text{ nm}$) being chemisorbed by hydrogen bonds to $\text{NbO}_x(\text{OH})_y$, adsorbate covered dust is found. This dust yields enhanced field emission (EFE [7]) summarized in Sect. 3.1.

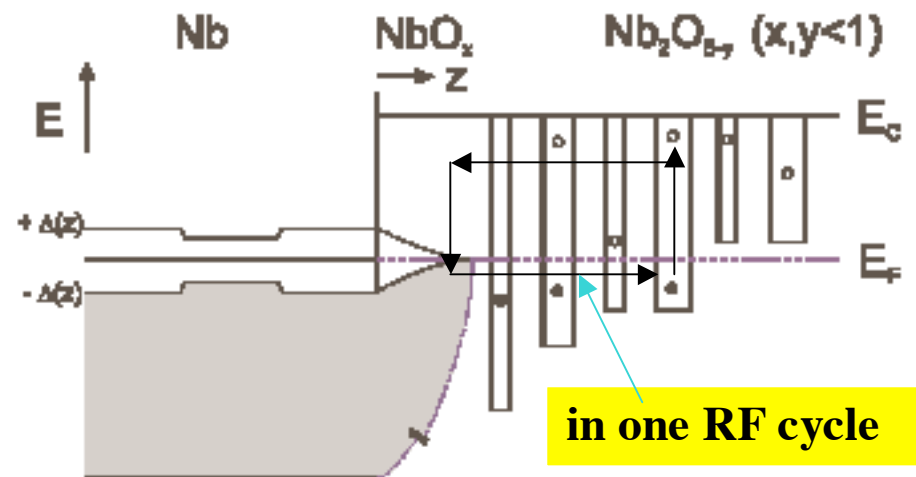


Fig. 3: Band structure at $\text{Nb-NbO}_x\text{-Nb}_2\text{O}_{5-y}$ interfaces with $E_C - E_F = \phi \approx 0.1 - 1 \text{ eV}$ as barrier heights for tunneling along crystallographic shear planes ($\sim 0.1 \text{ eV}$) or of $\text{Nb}_2\text{O}_{5-y}$ crystallites ($\sim 1 \text{ eV}$). Added is the superconducting energy gap $\Delta^*(z) < \Delta_0$ being reduced in NbO_x clusters or interfaces and being normal conducting $\Delta^*(z_L \geq 0.5 \text{ nm})$ in localized states of $\text{Nb}_2\text{O}_{5-y}$. By their volume expansion those clusters locally enhance T^* and $\Delta^* > \Delta_0$ in adjacent Nb by the uniaxial strain yielding a smeared BCS DOS.

Disease	Phenomena	Cures
Thermal instability	Quench at bad spot	Mechanical grinding, Use high pure niobium material Sever material control
Multipacting	Q-drop at discrete field levels (Electron resonant loading), Heating around equator section X-ray	Make clean surface Use spherical shape
Field emission	Exponential Q-drop with gradient (Electron non resonant loading) Heating on meridian X-ray	Make clean and smooth surface Use ultrapure water Use clean room assembly High pressure water rinsing
Hydrogen Q-disease	Low Q from low field, Depends on cooling speed	Annealing
Q-slope	Exponential Q-degradation without / with x-ray	Baking